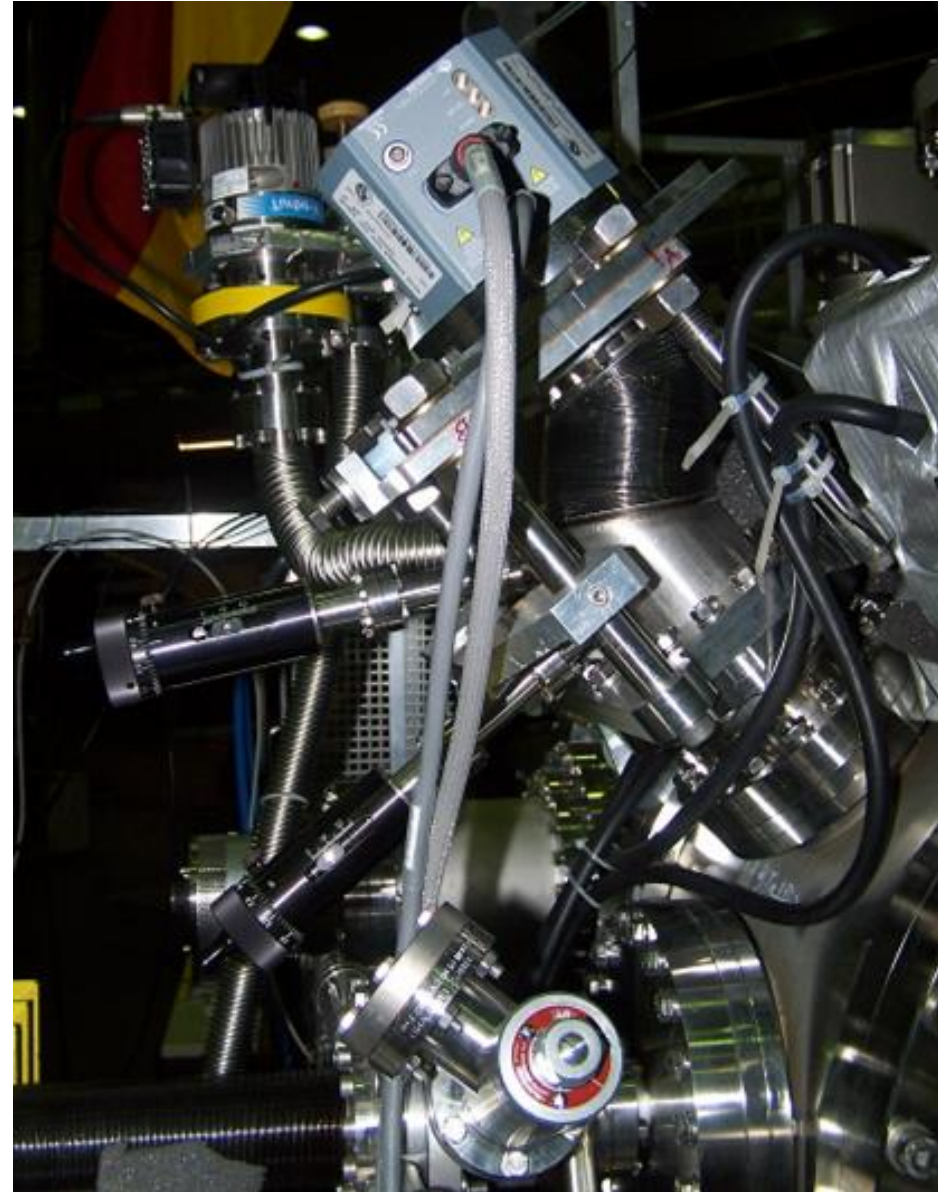
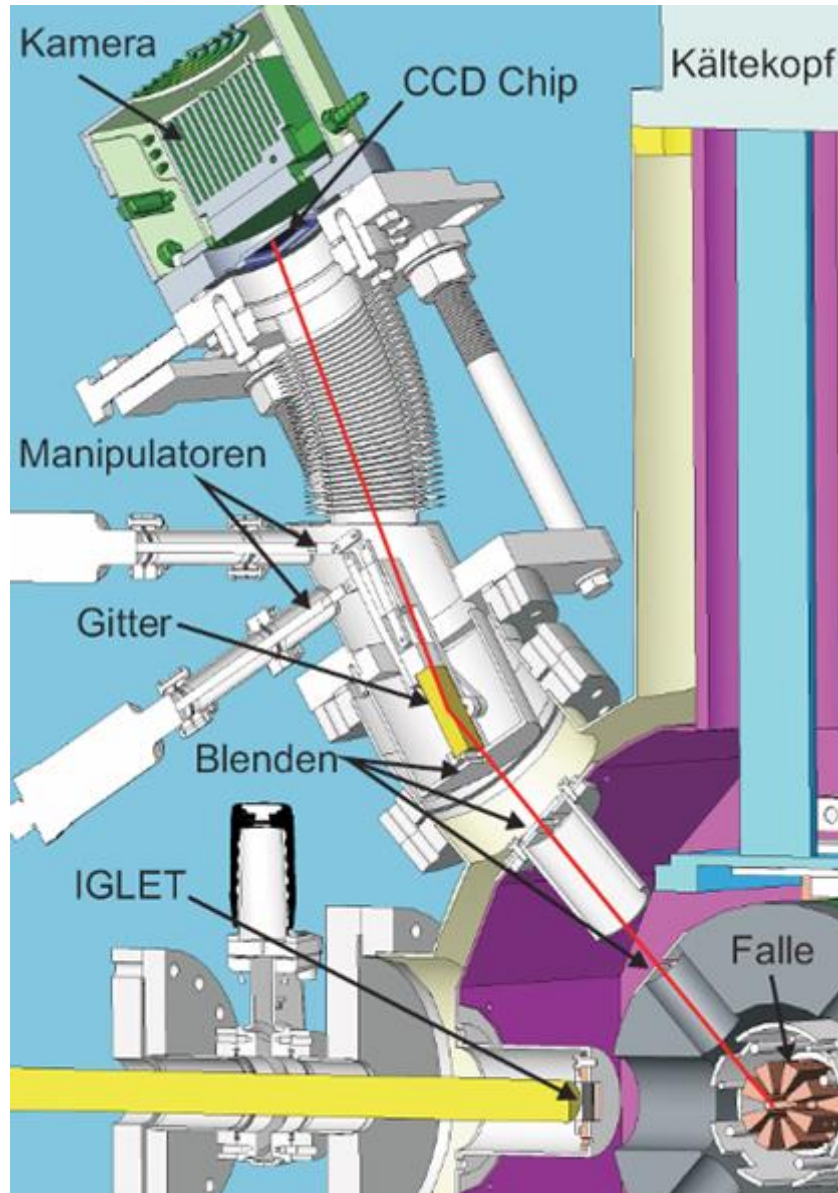
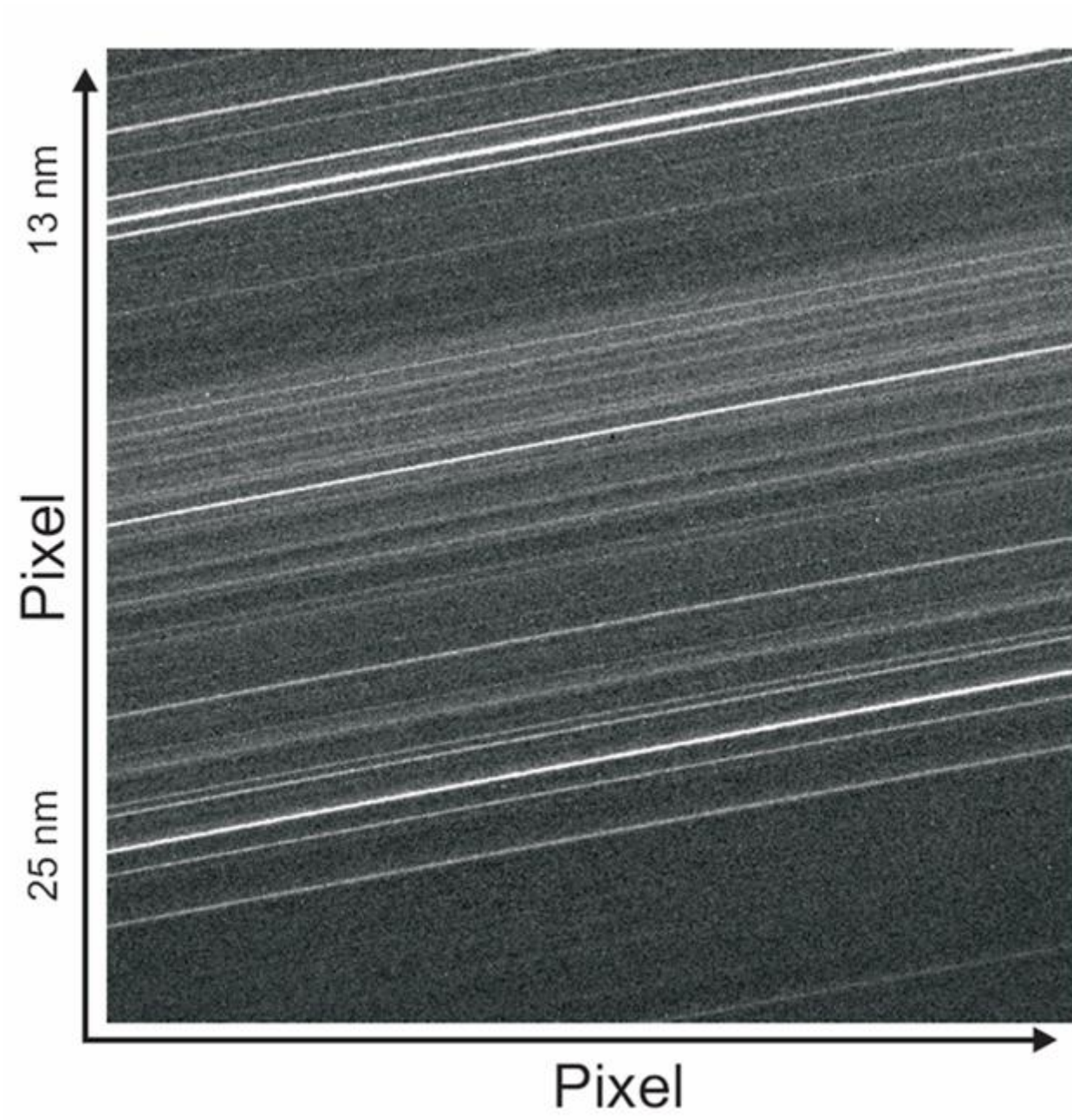


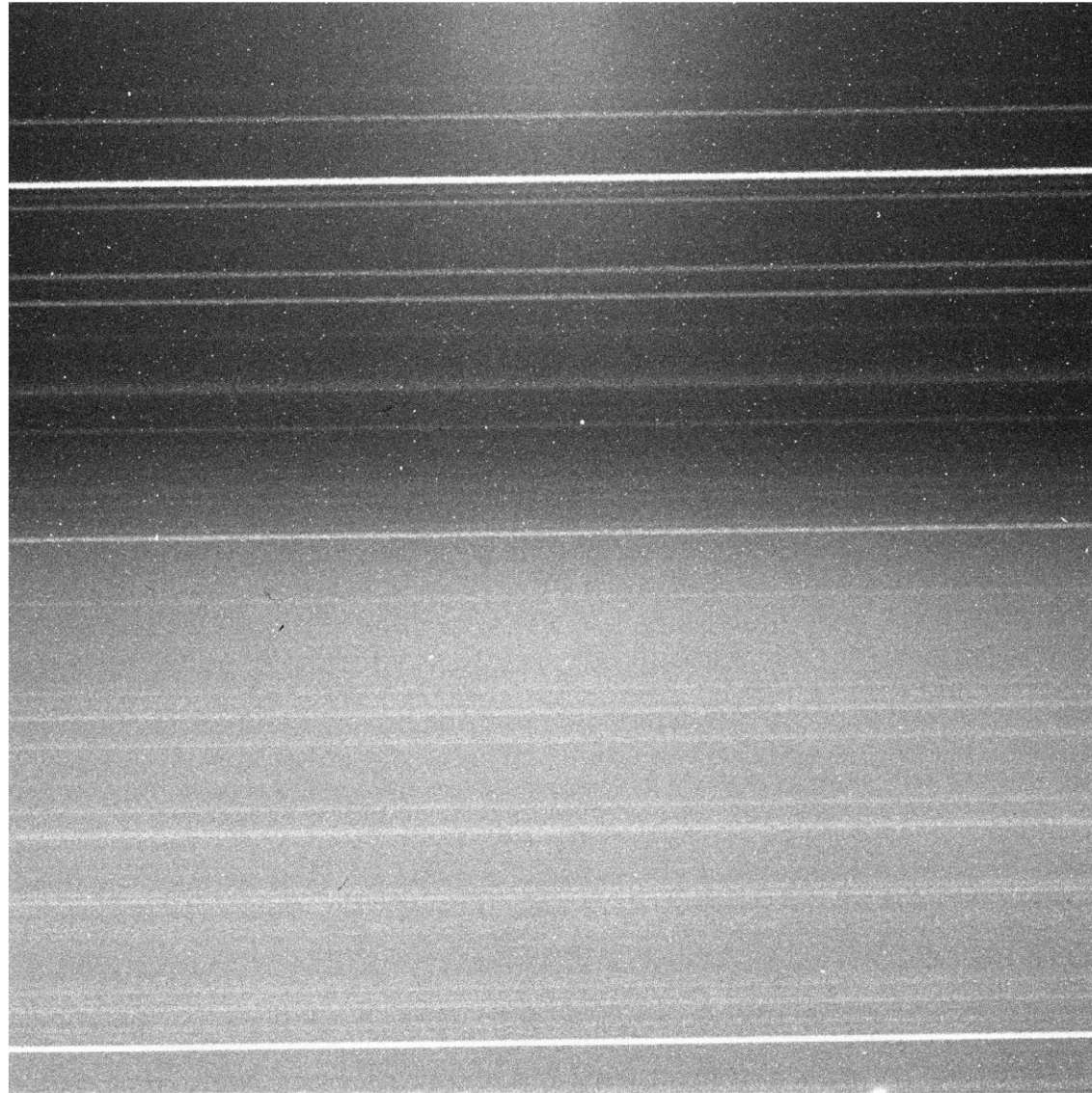
The compact FFGS (or CFFGIVUVS)



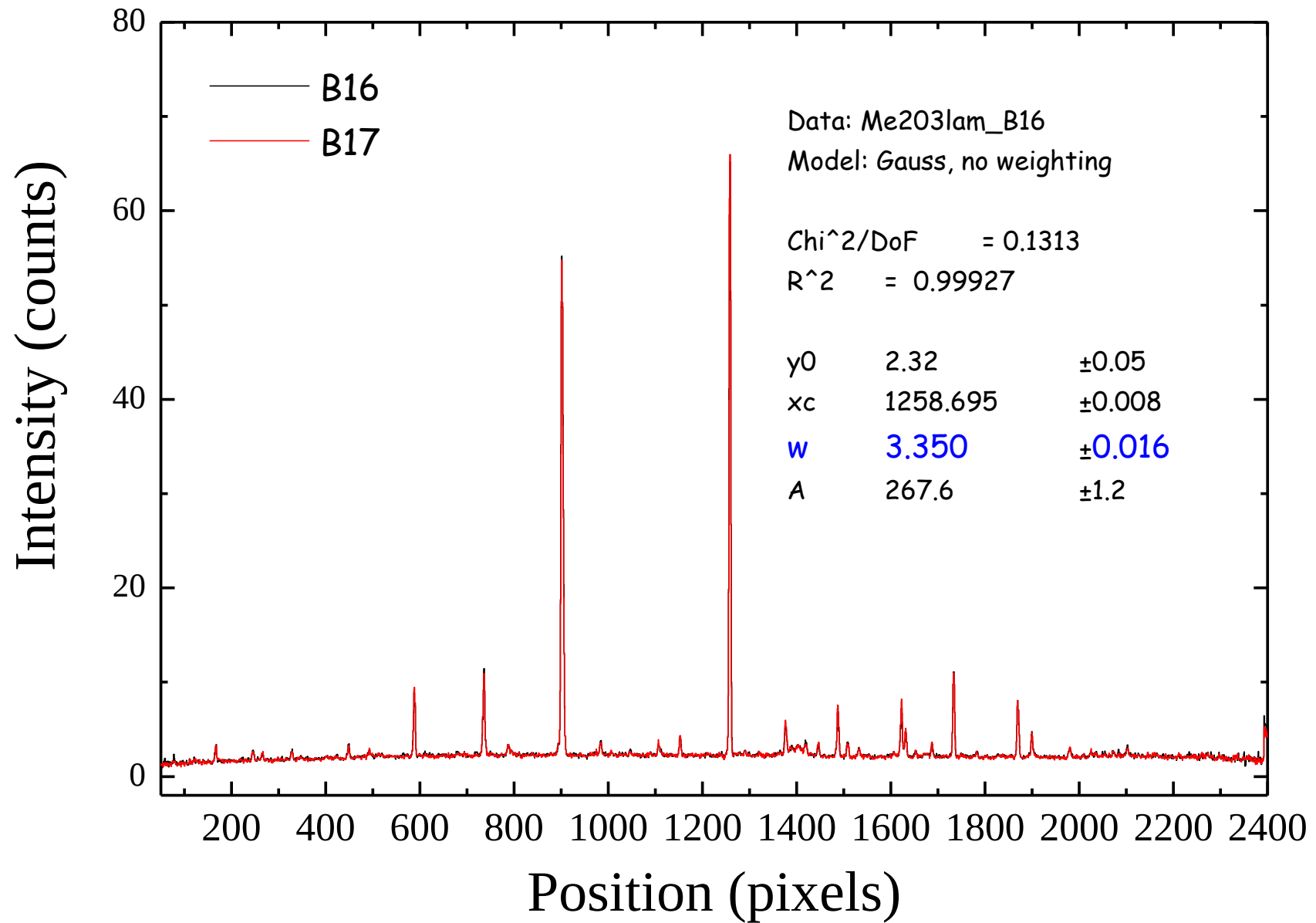
Spectral image (untreated)



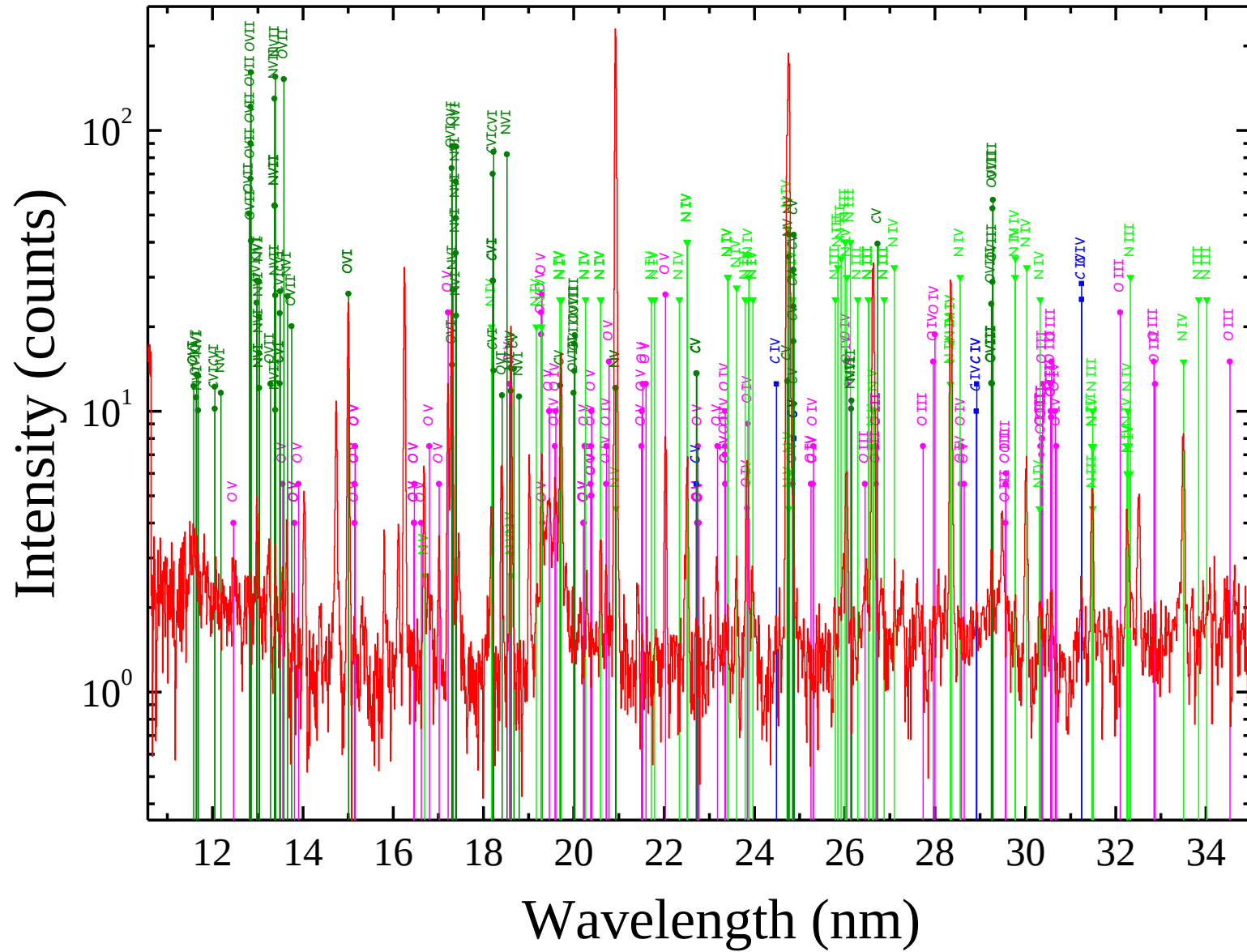
CCD spectral image



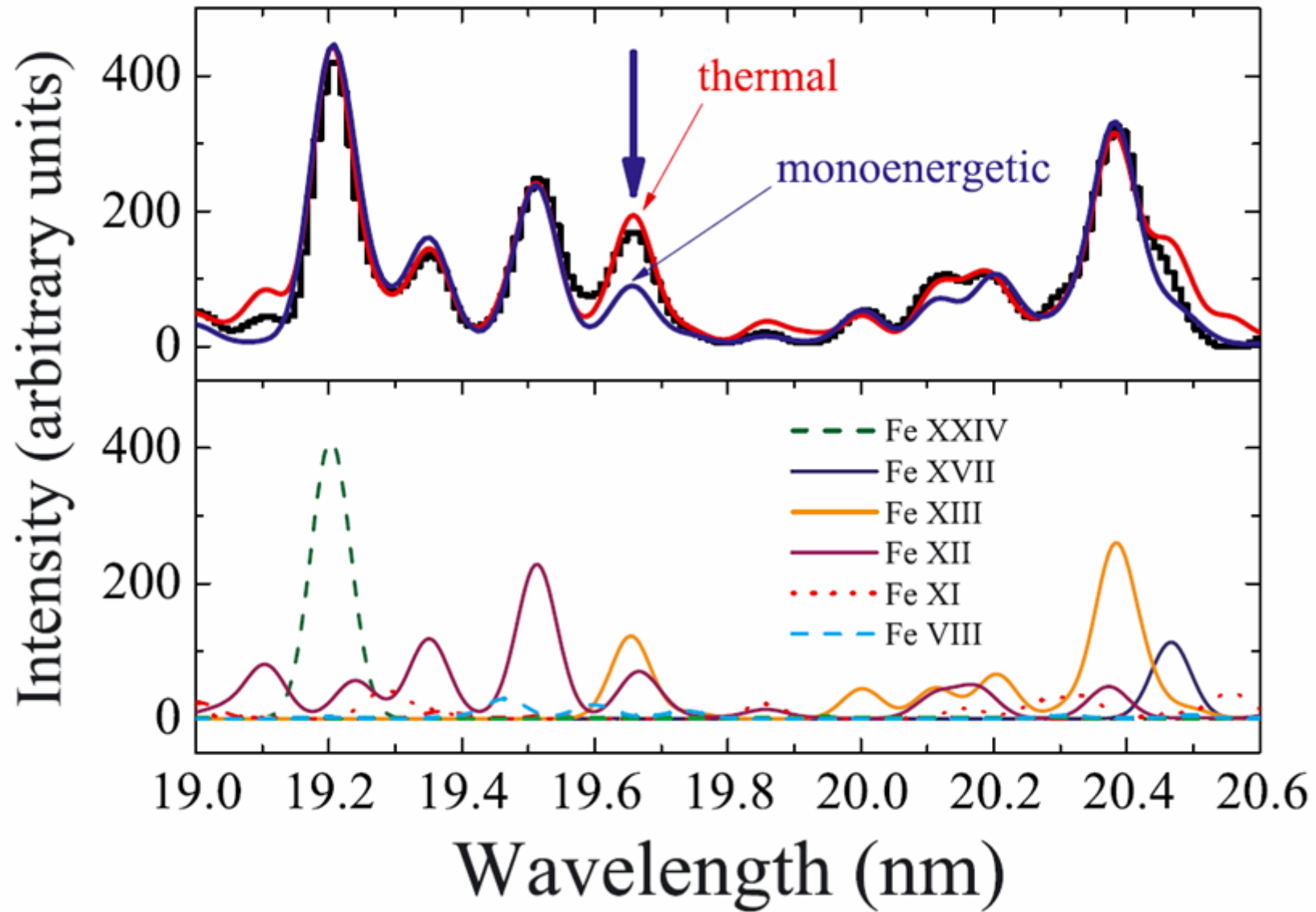
Resolving power



Calibration lines of O and N

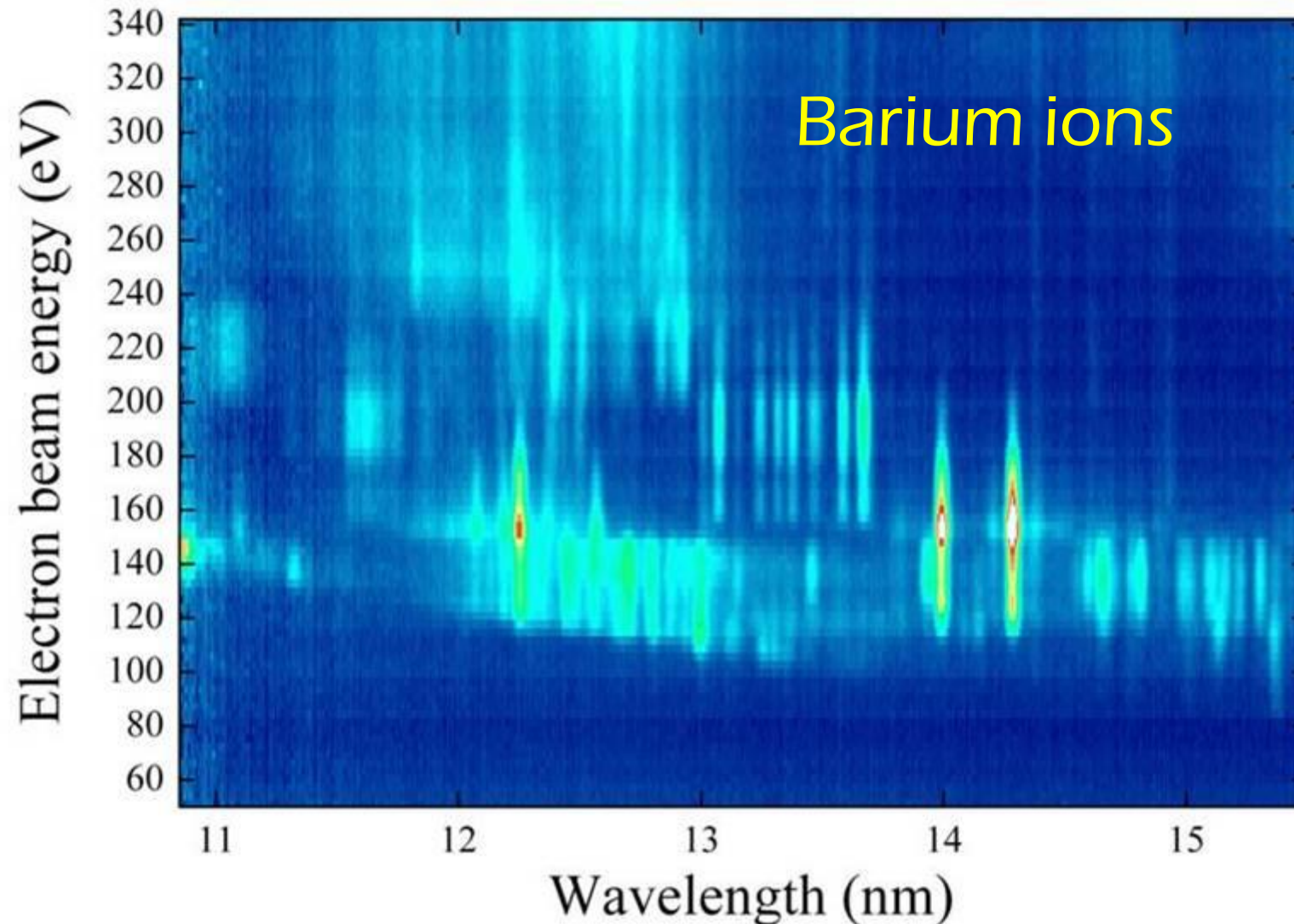


Spectral simulations with CHIANTI compared with data

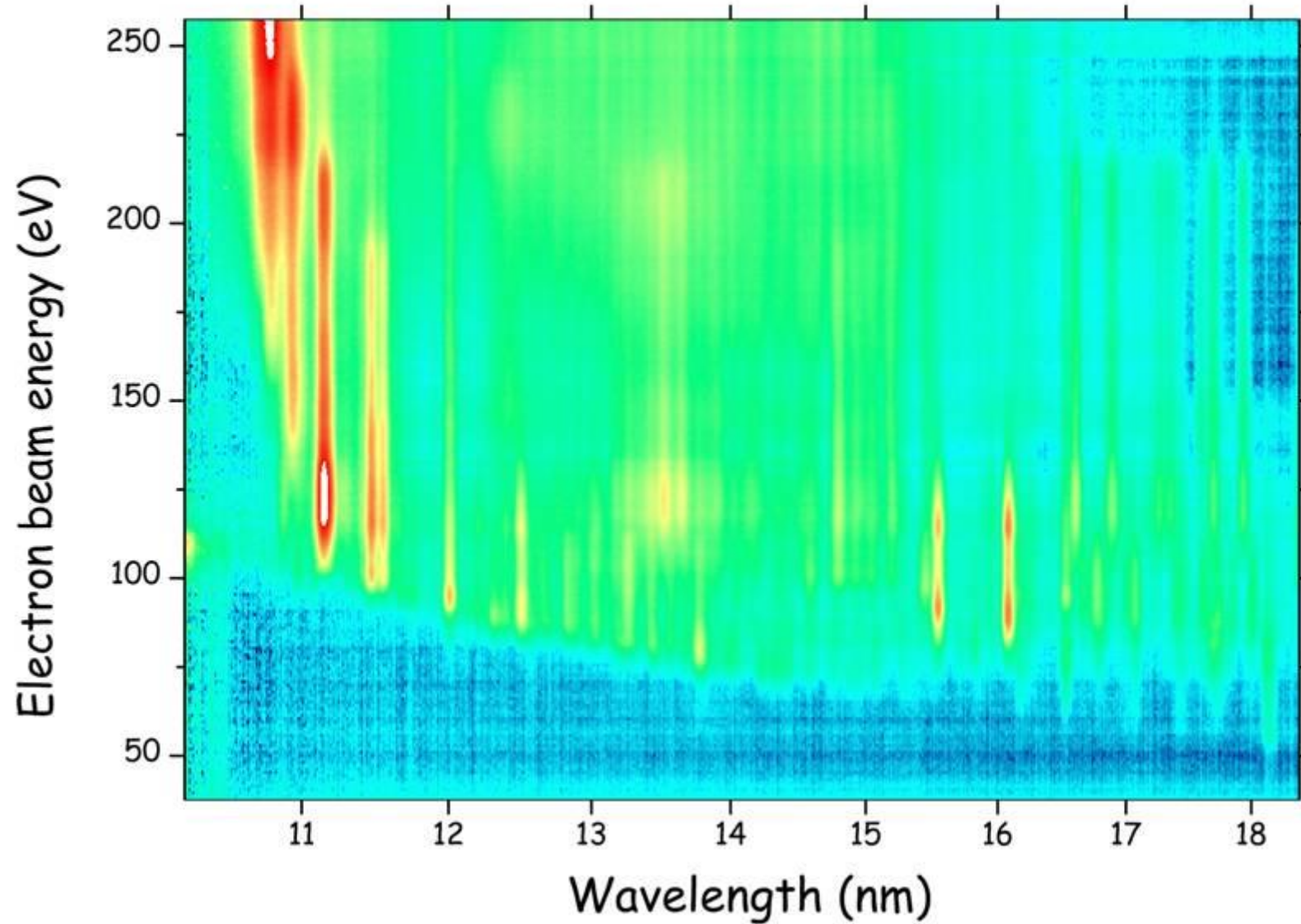


VUV spectra energy dependence

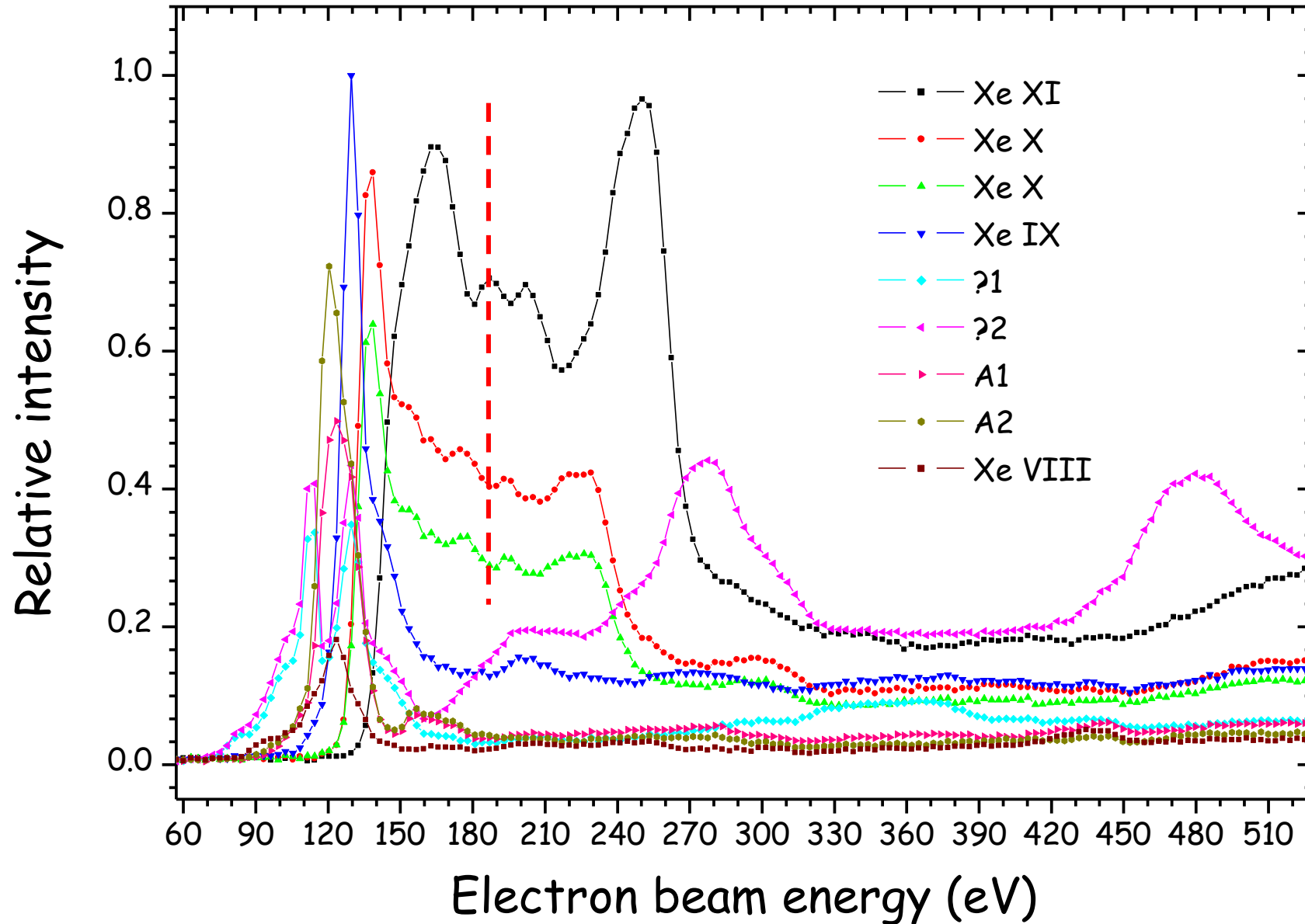
The spectra are monitored as the electron beam energy is varied in steps of 3 eV shown together in a composite image.

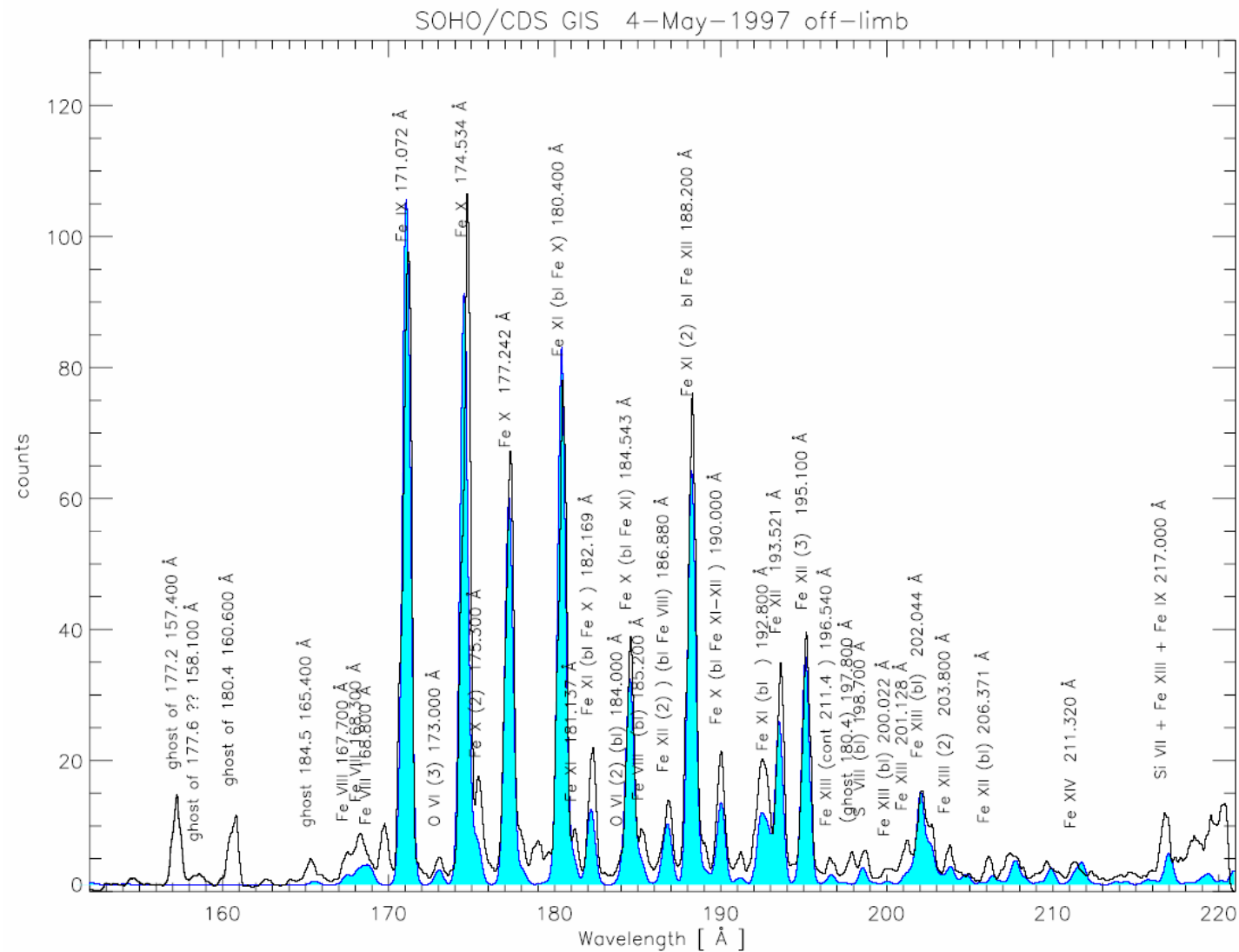


Xenon for microlithography



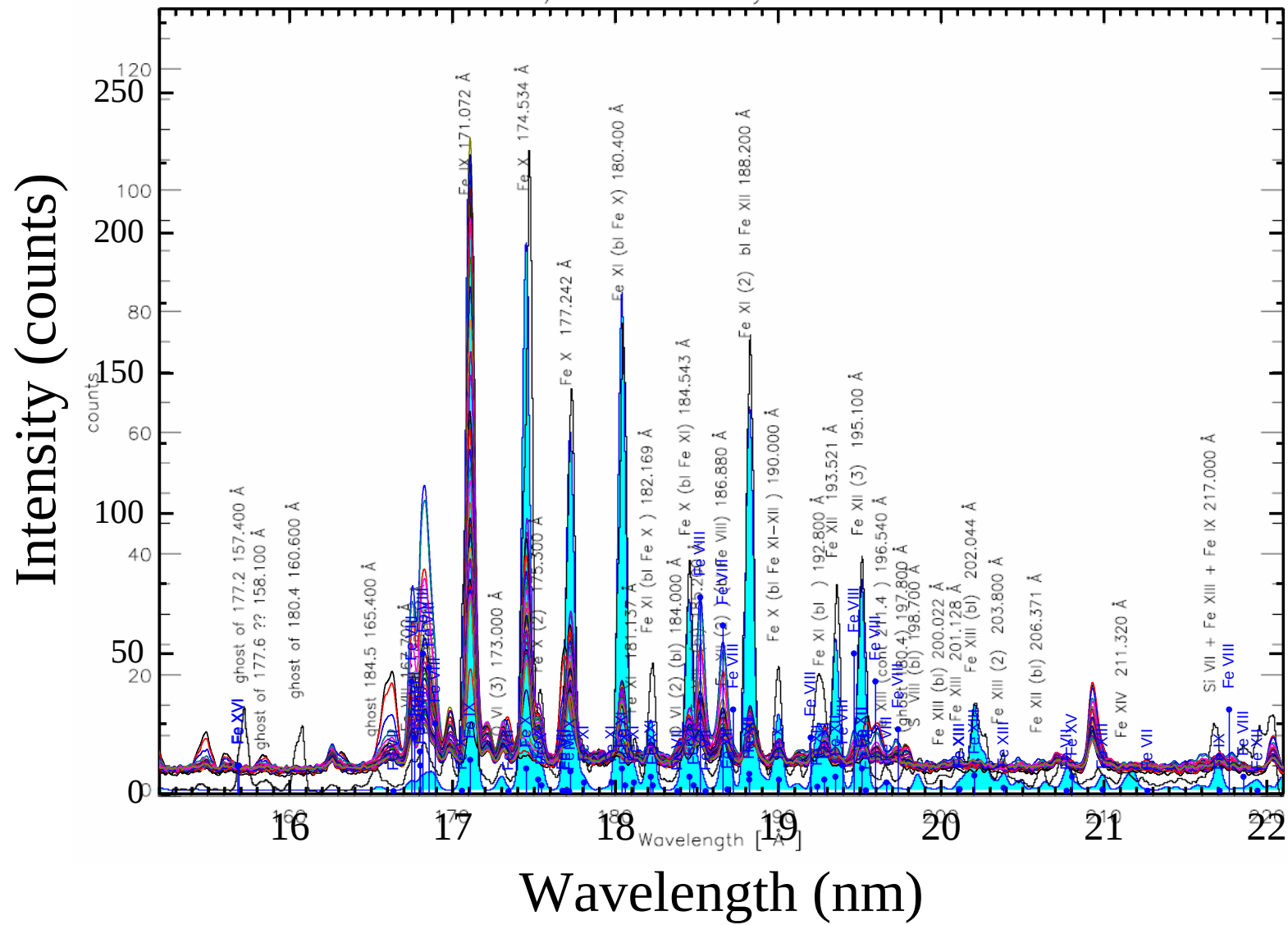
Excitation energy dependency

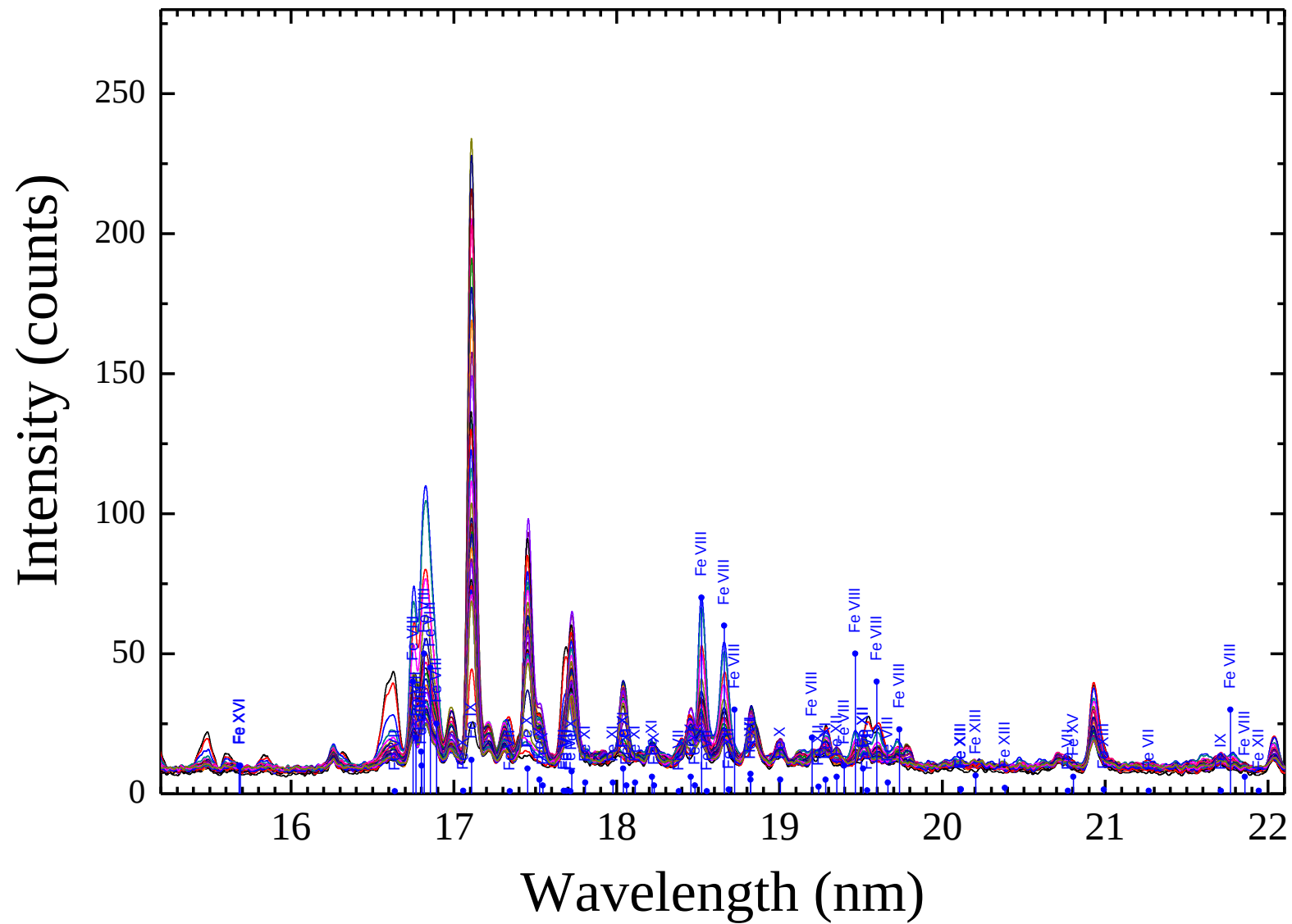


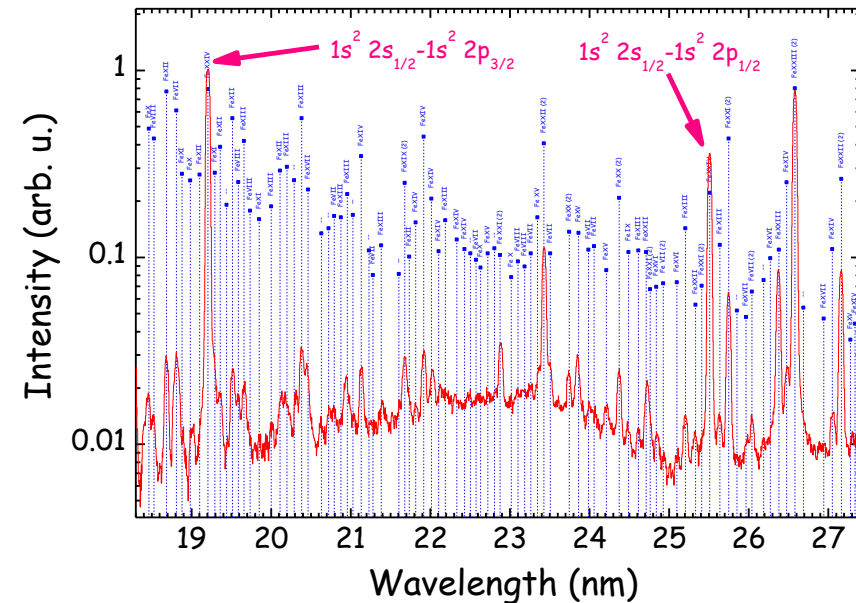


GIS 1 spectrum of an off-limb quiet sun observation (May 4th 1997), with corresponding synthetic spectra overlaid. These types of spectra have been mainly used for the first order internal and cross-detector calibration.

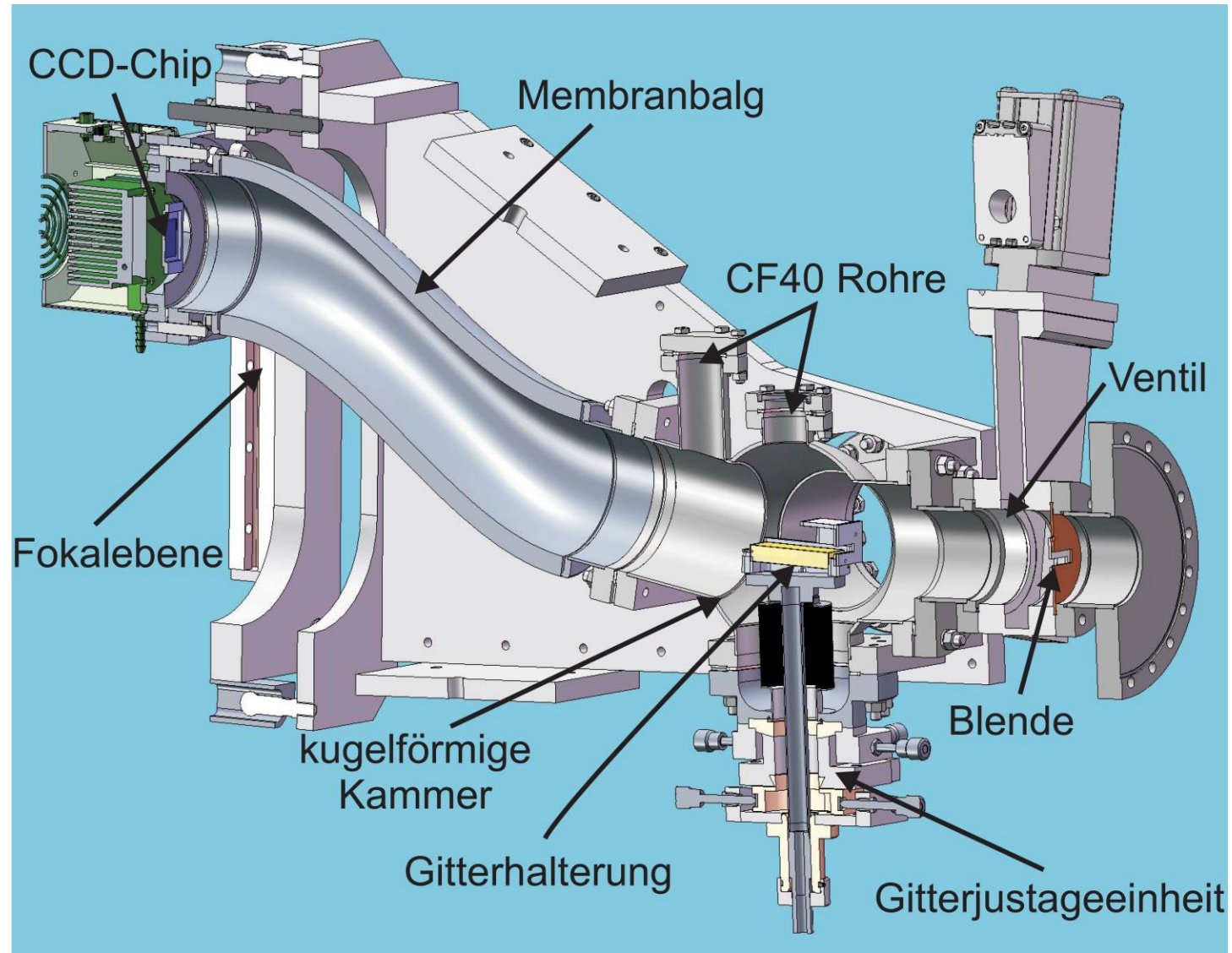
G. Del Zanna, B. J. I. Bromage, E. Landi, and M. Landini, A&A 379, 708 (2001)



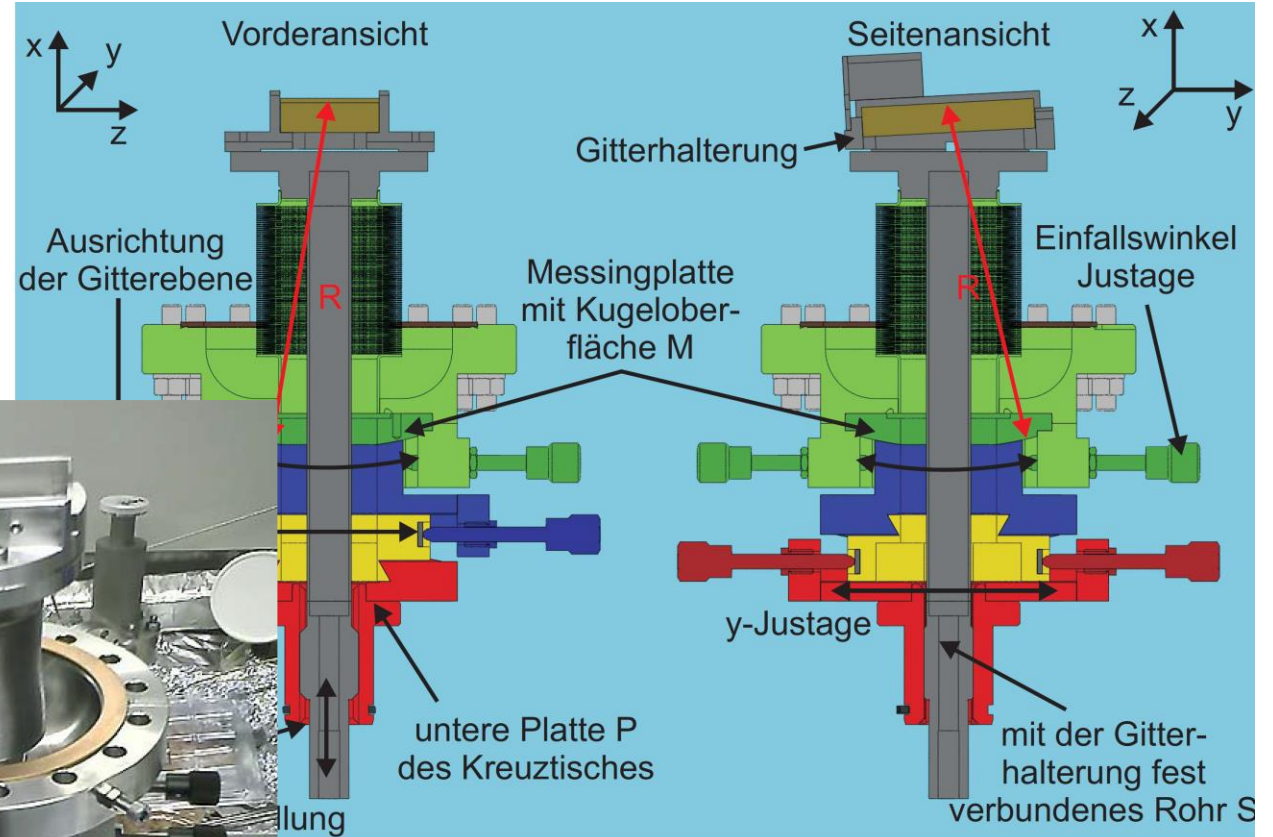
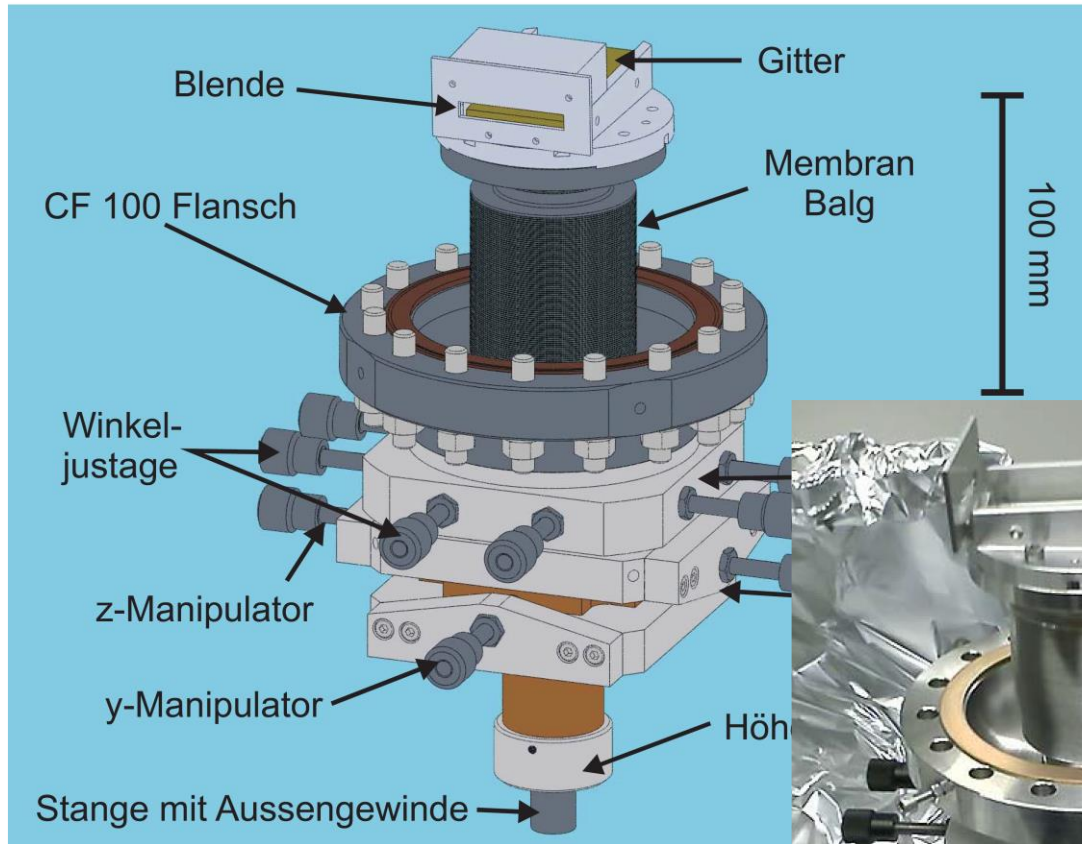




The new flat field grating spectrometer (Baumann 2008)

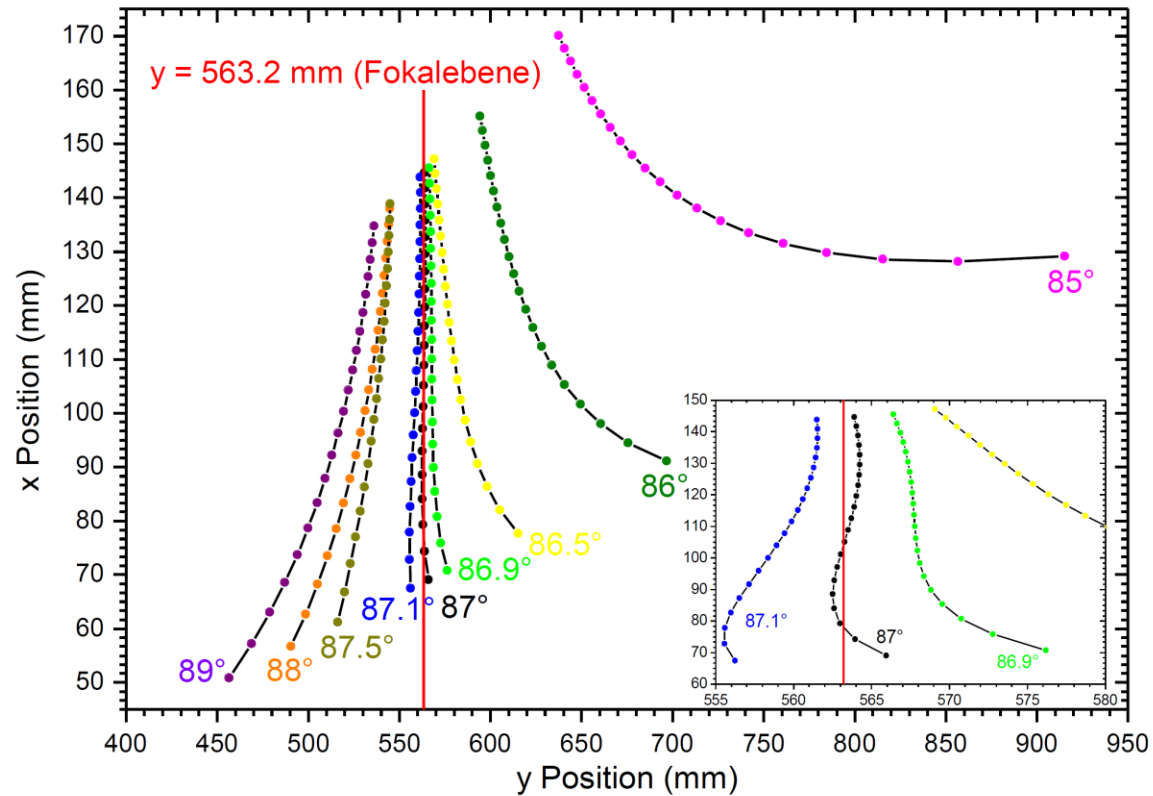


The new flat field grating spectrometer (Baumann 2008)

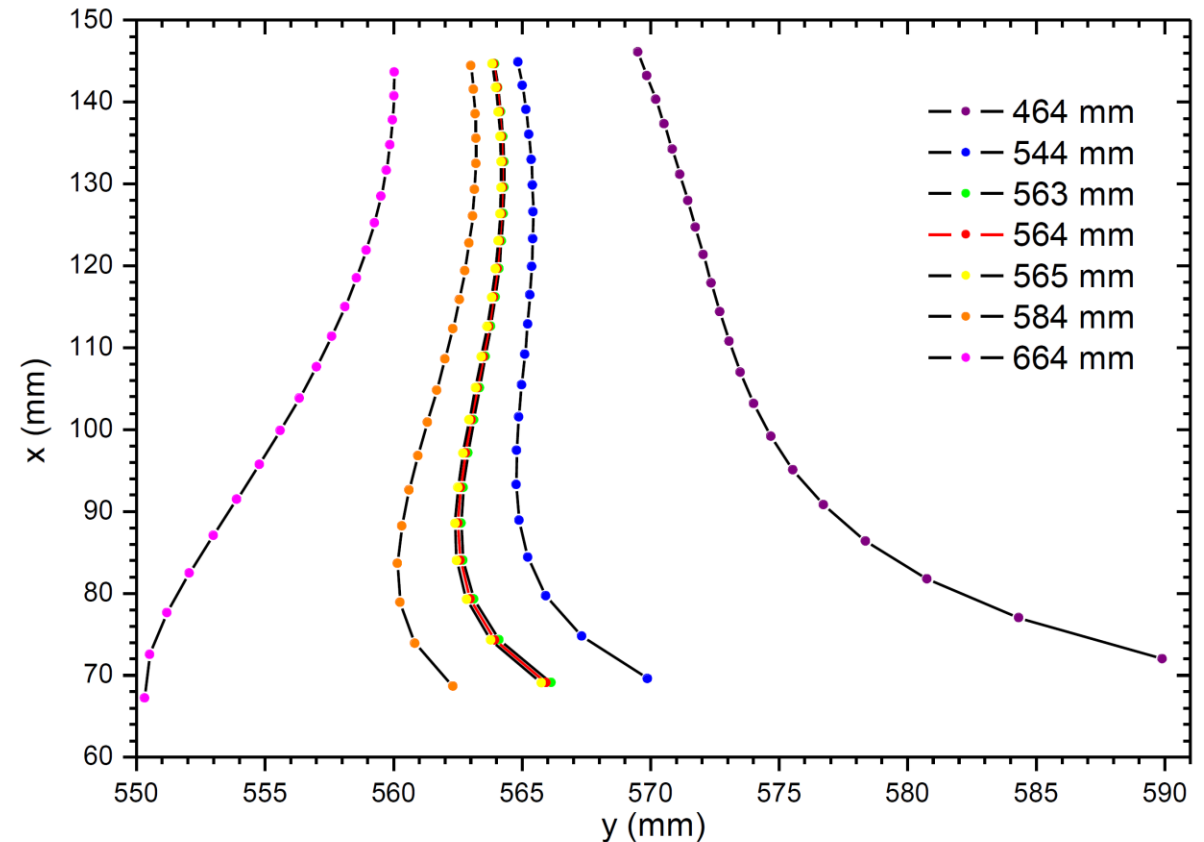


Thomas Baumann
2008

Focal plane of flat field grating spectrometer (Baumann 2008)

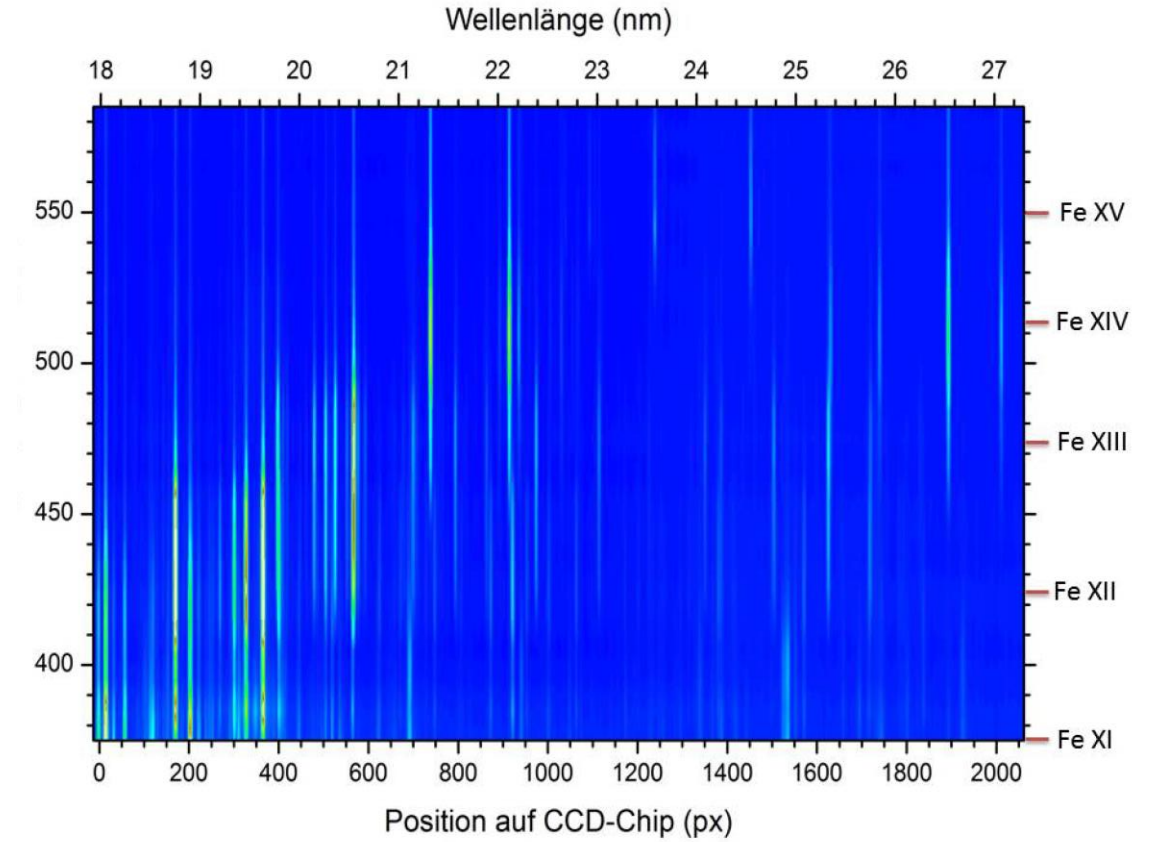
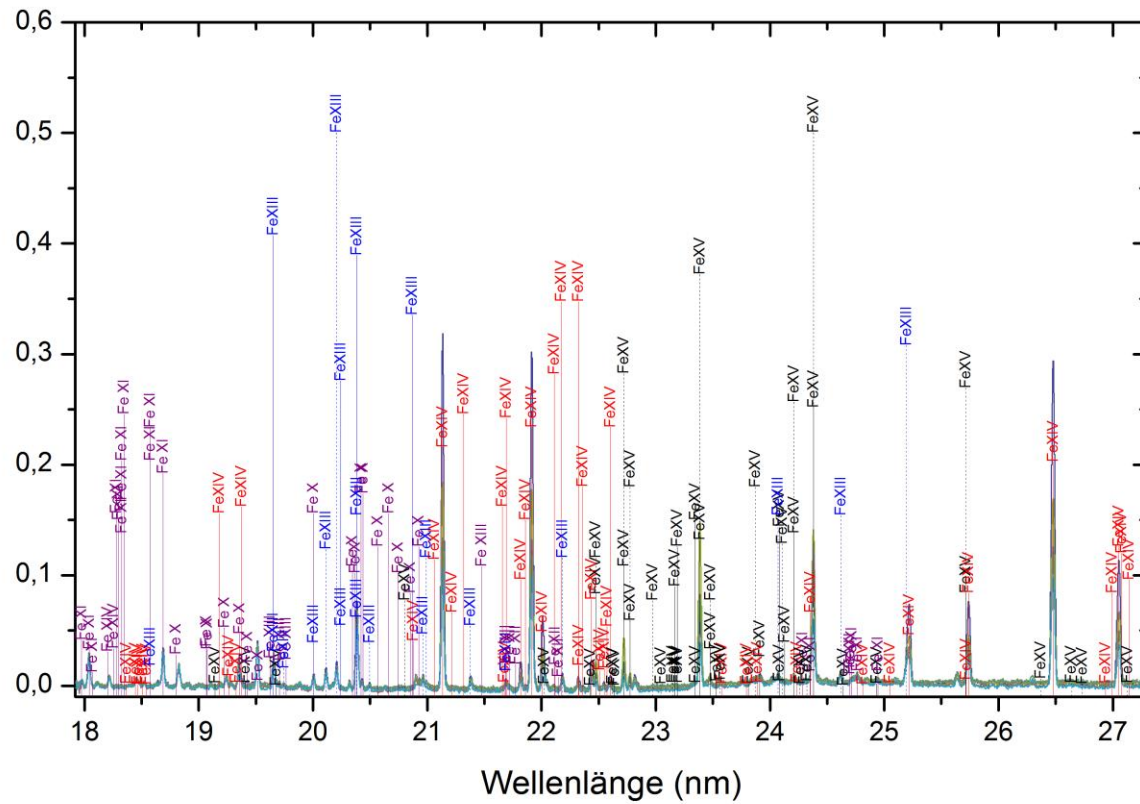


Horizontale Fokalkurven von Gitter II für unterschiedliche Einfallswinkel. Der kleine Graph zeigt den vergrößerten Bereich um 87°

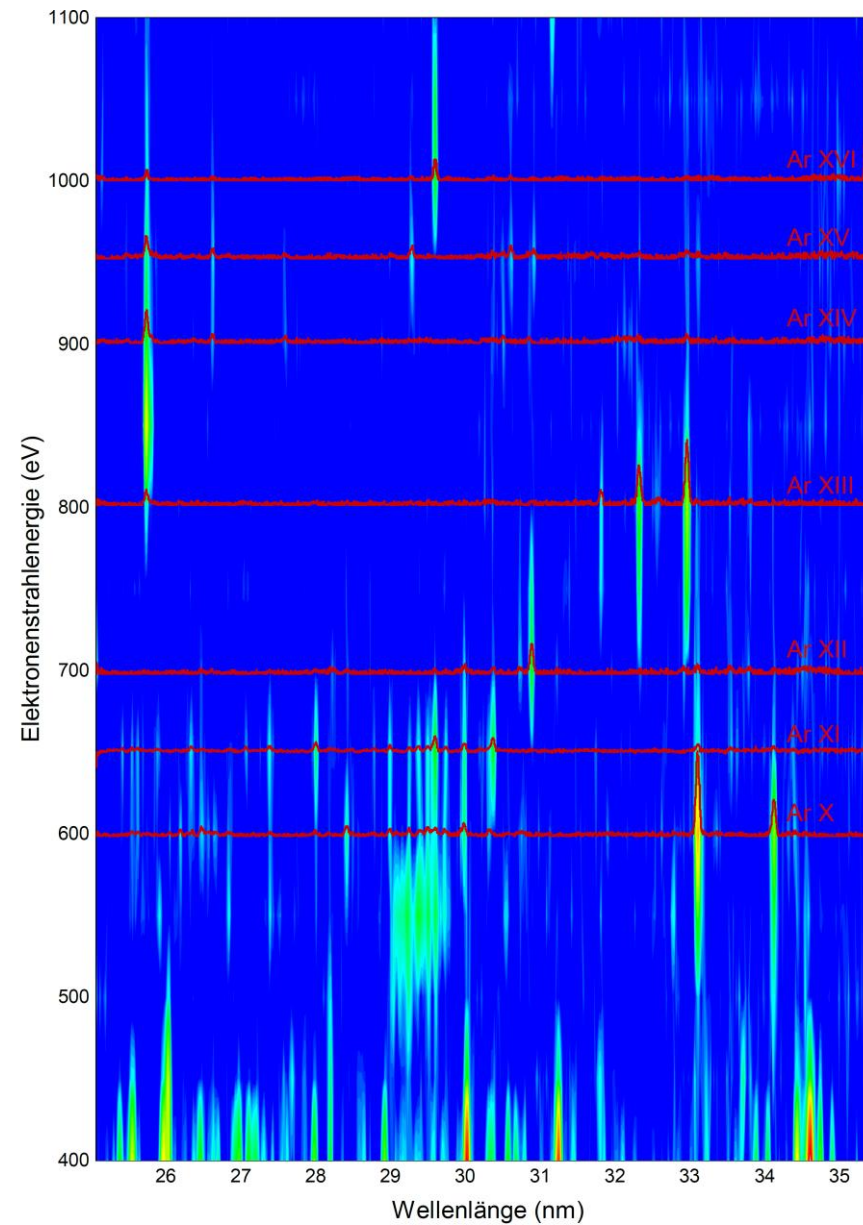


Fokalkurven von Gitter II für unterschiedliche Quellendistanzen r

Selectivity of charge states with electron beam energy



Selectivity of charge states with electron beam energy



Reproducibility and error bars in the XUV

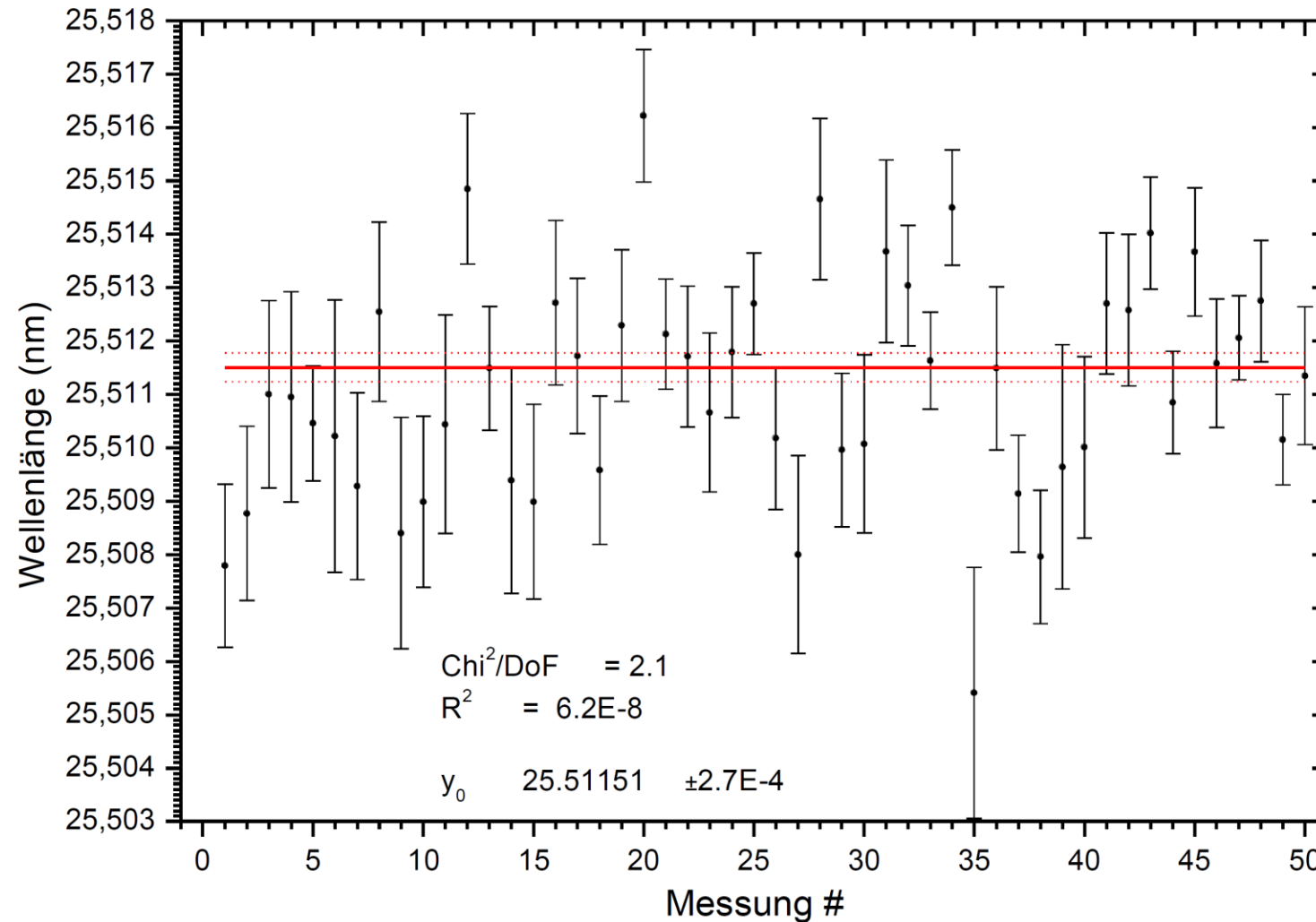


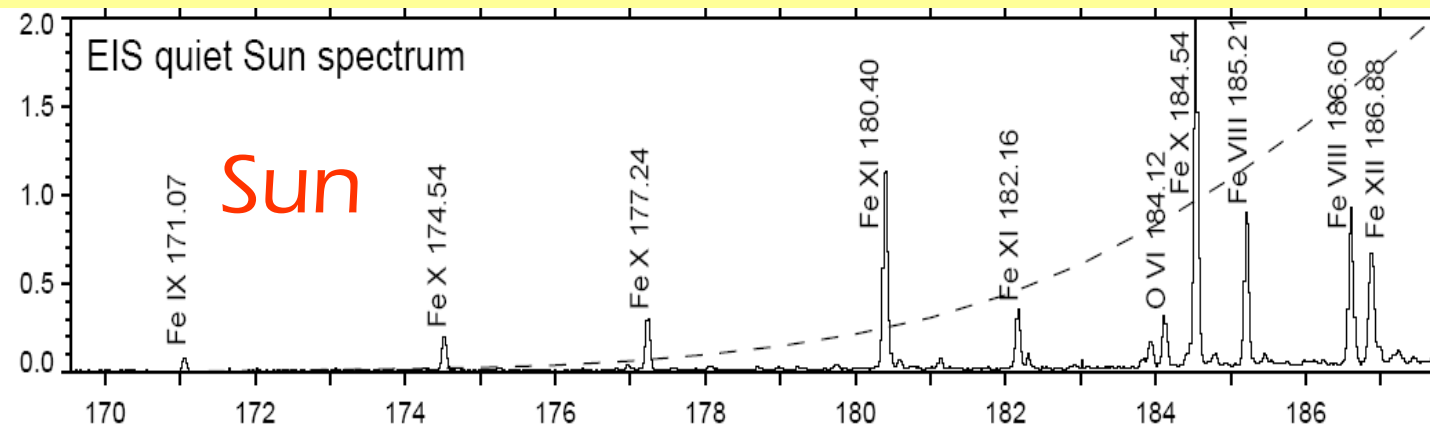
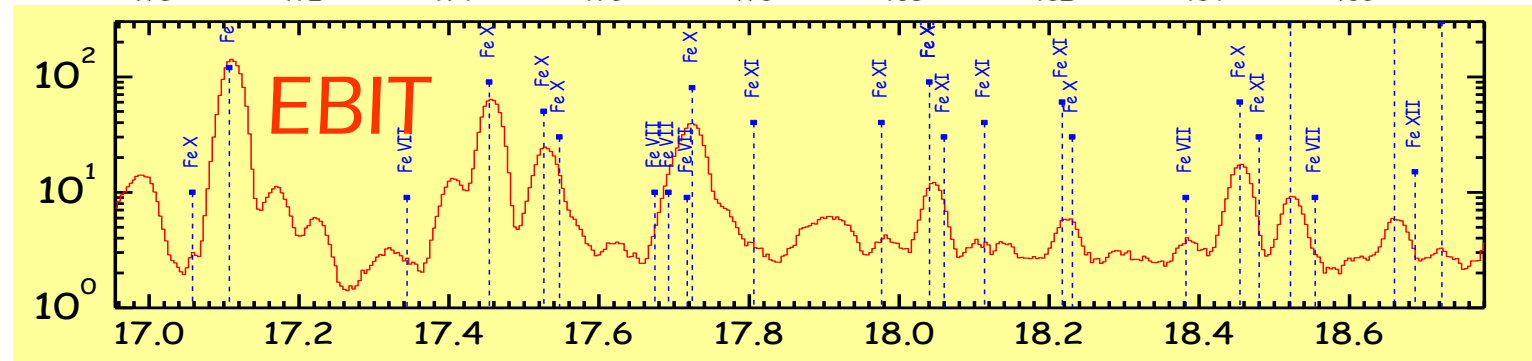
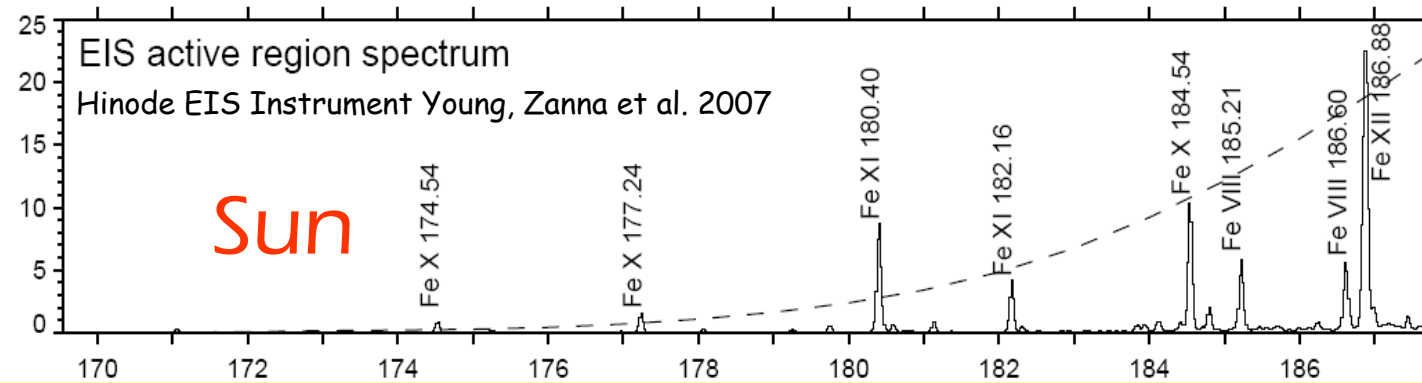
Abbildung 5.14: Wellenlänge des $1s^22s\ S_{1/2} - 1s^22p\ P_{3/2}$ Übergangs in Fe XXIV aller 50 Messungen zusammen mit ihrem statistisch gewichteten Mittelwert und dessen 68% Vertrauensintervall.

Reproducibility and error bars in the XUV

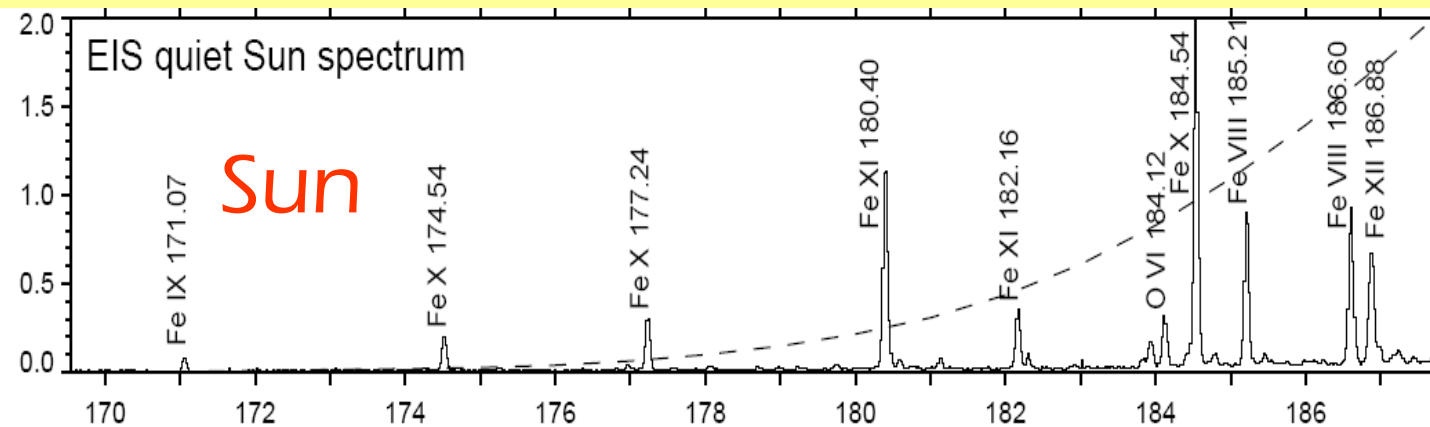
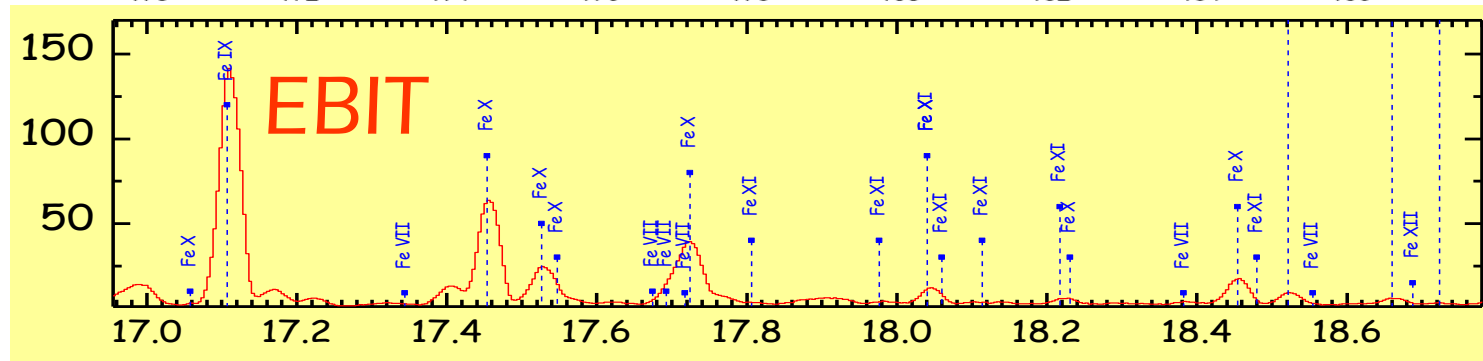
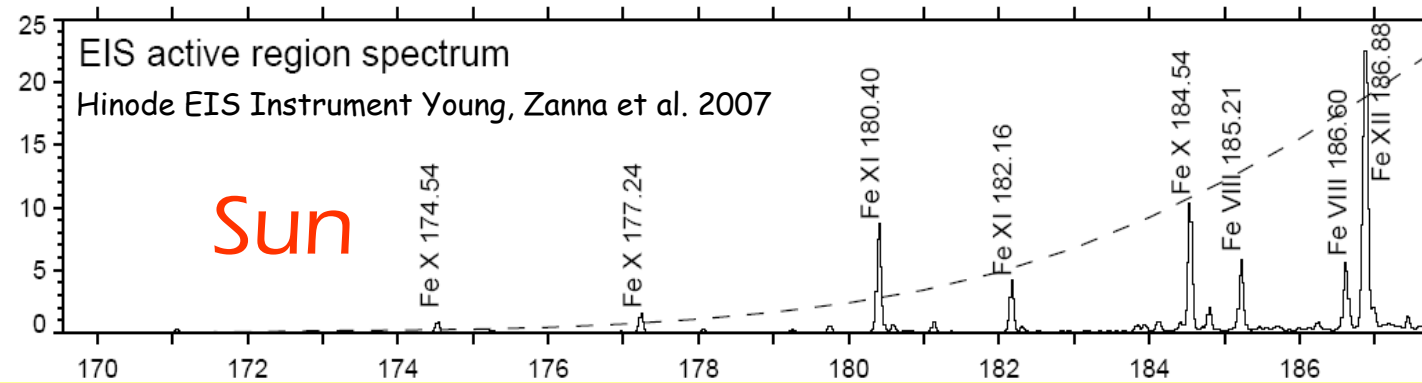
Referenz	Wellenlänge λ (nm)	Fehler $\Delta\lambda$ (nm)	Methode
K. Dere 1978 [41]	19.203	0.003	Sonneneruption
E. Hinnov 1979 [42]	19.205	0.003	Tokamak
E. Hinnov 1989 <i>et al.</i> [43]	19.201	0.002	Tokamak
R. J. Knize 1991 [44]	19.2046	0.0009	Tokamak
J. Reader 1994 <i>et al.</i> [37]	19.2028	0.0005	Tokamak
S. W. Epp 2007 [10]	19.2017	0.0012	EBIT
S. A. Blundell 1993 [45]	19.2021		Theorie
M. H. Chen 1995 [46]	19.205		Theorie
diese Arbeit	19.2037	0.001	EBIT
K. P. Dere 1978 [41]	25.511	0.003	Sonneneruption
E. Hinnov 1979 [42]	25.511	0.003	Tokamak
E. Hinnov 1989 <i>et al.</i> [43]	25.509	0.001	Tokamak
R. J. Knize 1991 [44]	25.511	0.001	Tokamak
J. Reader 1994 <i>et al.</i> [37]	25.5113	0.0005	Tokamak
S. W. Epp 2007 [10]	25.5118	0.0002	EBIT
S. A. Blundell 1993 [45]	25.5101		Theorie
M. H. Chen 1995 [46]	25.5111		Theorie
diese Arbeit	25.5115	0.0007	EBIT

Tabelle 5.4: Literaturwerte der beiden Fe XXIV Linien. Zur Messung dieser Linien wurden unterschiedliche Methoden angewandt: Spektrale Untersuchungen von Sonneneruptionen, Spektroskopie an Tokamak Plasmen, Spektroskopie an EBIT Plasmen und theoretische Berechnungen.

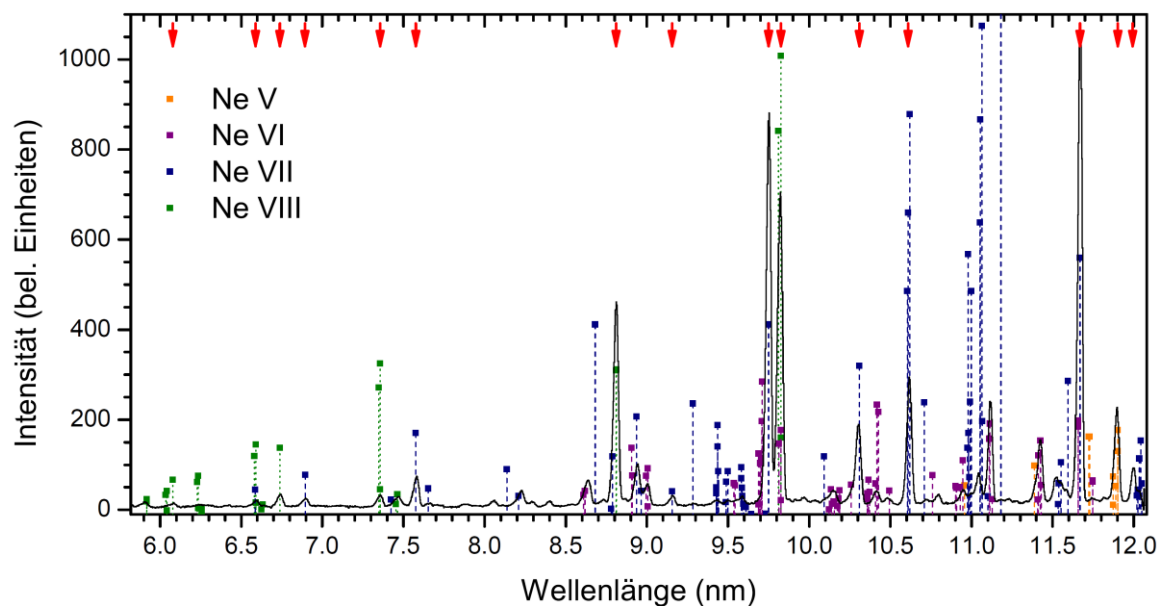
Hinode ("sunrise") is a solar space telescope mission launched in 2006 (Japan with US and UK partners) aiming at investigating the Sun's corona



Hinode ("sunrise") is a solar space telescope mission launched in 2006 (Japan with US and UK partners) aiming at investigating the Sun's corona

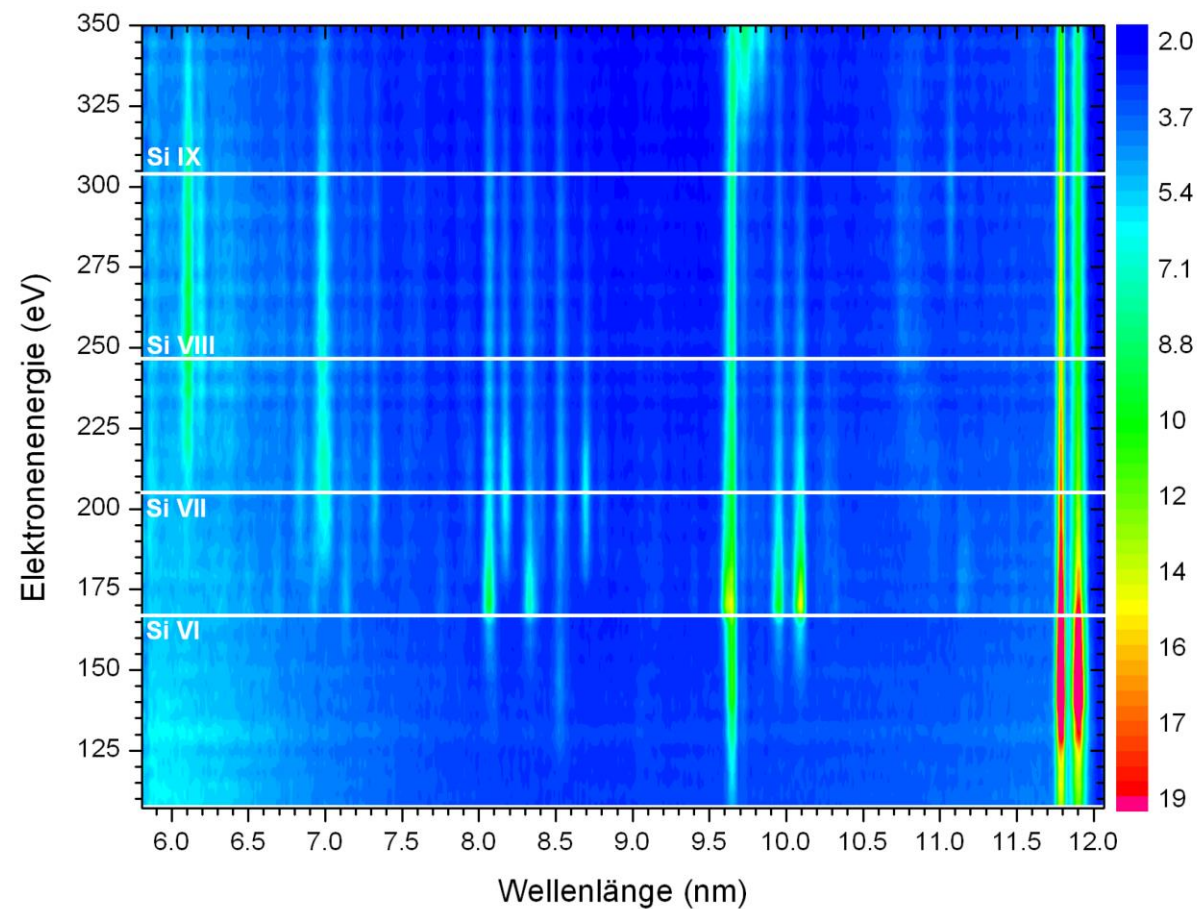
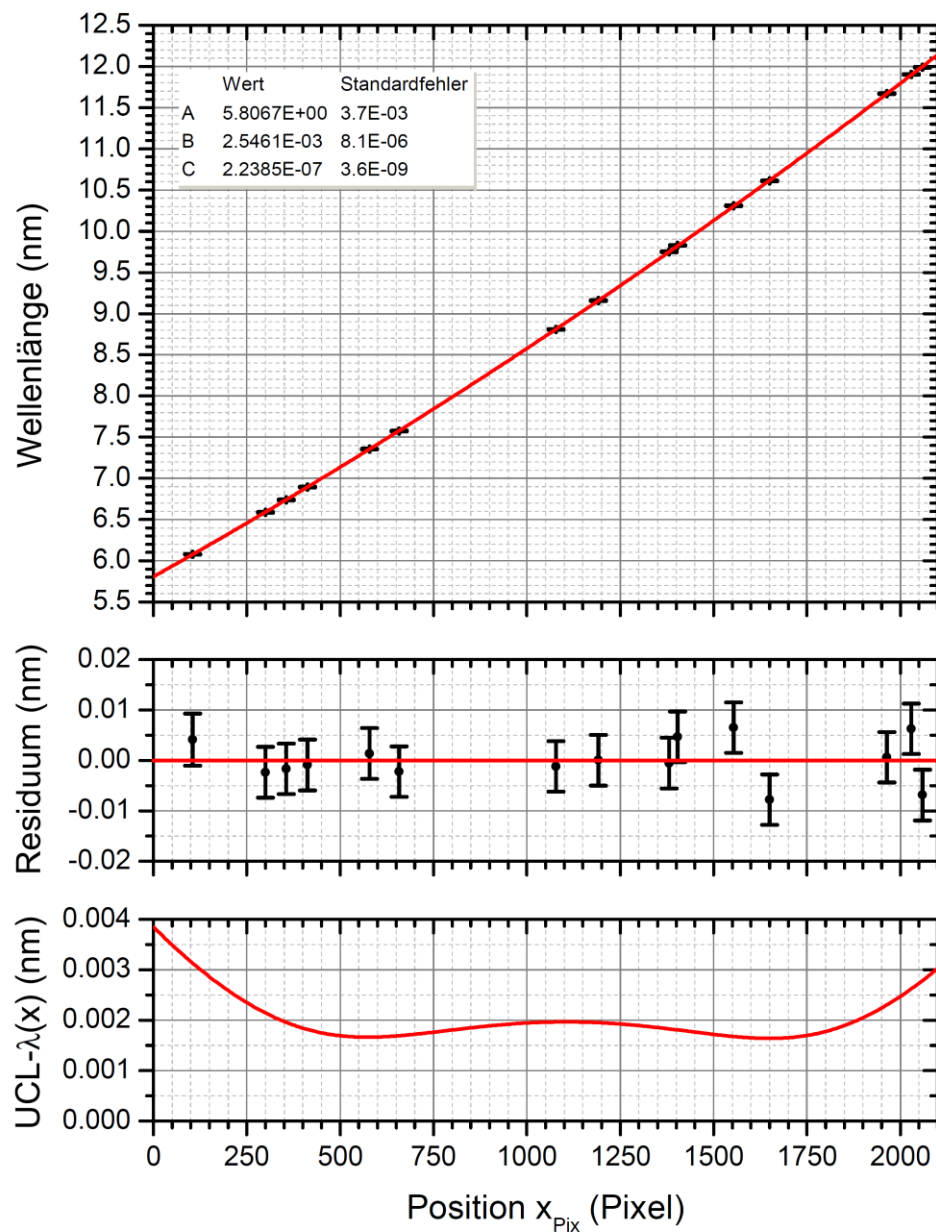


Reproducibility and error bars in the XUV



Ion	Wellenlänge	Position (Pixel)	Gesamtfehler
Ne VI	11,992 nm	2059,2(2)	0,005 nm
Ne V	11,901 nm	2029,12(9)	0,005 nm
Ne VII	11,669 nm	1963,4(1)	0,005 nm
Ne VII	10,61 nm	1649,76(1)	0,005 nm
Ne VIII	10,31 nm	1553,58(9)	0,005 nm
Ne VIII	9,826 nm	1403,58(8)	0,005 nm
Ne VIII	9,75 nm	1381,29(7)	0,005 nm
Ne VII	9,156 nm	1190,9(2)	0,005 nm
Ne VIII	8,809 nm	1077,63(7)	0,005 nm
Ne VII	7,577 nm	1657,9(1)	0,005 nm
Ne VIII	7,356 nm	578,6(2)	0,005 nm
Ne VII	6,89 nm	412,44(2)	0,005 nm
Ne VIII	6,738 nm	355,4(2)	0,005 nm
Ne VIII	6,589 nm	300,4(2)	0,005 nm
Ne VIII	6,079 nm	104,6(5)	0,005 nm

Reproducibility and error bars in the XUV

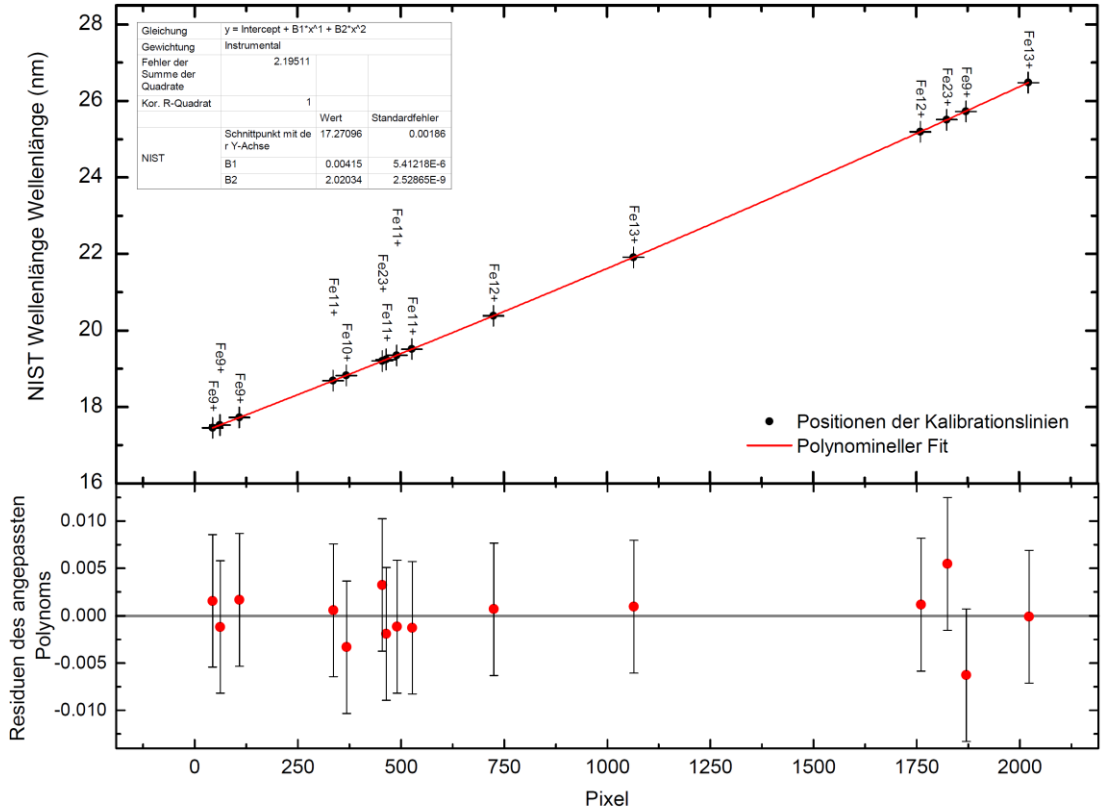


Ion	Übergang	Diese Arbeit λ (nm)	[185] λ (nm)	[186] λ (nm)
Si VIII	$3d^2F_{5/2} \rightarrow 2p^3^4S_{3/2}$	6,106(3)		6,1032
Si VIII	$3d^2F_{7/2} \rightarrow 2p^3^2D_{5/2}$	6,195(3)		6,1792
Si VI		6,490(3)		
Si VI	$5d^2D_{5/2} \rightarrow 2p^5^2P_{3/2}$	6,68(3)		6,6772 (NIST)
Si VII	$3d^5D_3 \rightarrow 2p^4^3P_1$	6,835(2)		6,8148
Si VI		6,932(2)		
Si VII	$3d^3F_2 \rightarrow 2p^4^3P_2$	6,990(2)		6,9664
Si VII	$3d^3F_3 \rightarrow 2p^4^1D_2$	7,014(2)		7,0072
Si VII	$3d^3G_3 \rightarrow 2p^4^1D_2$	7,136(2)		7,1384
Si VII	$3d \rightarrow 2p^4$	7,324(2)		7,312
Si VI	$3d \rightarrow 2p^5$	7,759(2)		7,7429 / 7,7718
Si V	$5d^1P_1^o \rightarrow 2p^6^1S_0$	8,055(2)	8,054(2)	
Si VI	$3d \rightarrow 2p^5$	8,067(2)		8,0449 / 8,0725
Si V	$5d^3D_1^o \rightarrow 2p^6^1S_0$	8,098(2)	8,078(1)	
Si VII	$3s \rightarrow 2p^4$	8,174(2)		8,1617 / 8,1845
Si VI	$3d^2D_{5/2} \rightarrow 2p^5^2P_{3/2}$	8,328(2)		8,3128
Si VI	$3d^2D_{3/2} \rightarrow 2p^5^2P_{1/2}$	8,378(2)		8,3611
Si VII	$3s1D_2 \rightarrow 2p^4^1D_2$	8,410(2)		8,4082
Si V	$4d^1P_1^o \rightarrow 2p^6^1S_0$	8,526(2)	8,5177(8)	
Si V	$4d^3D_1^o \rightarrow 2p^6^1S_0$	8,57(2)	8,558(1)	
Si VII		8,697(2)		
Si VII	$3s^3P_2 \rightarrow 2p^5^3P_2$	8,805(2)		8,8008
Si VI		9,618(2)		
Si V	$3d^1P_1^o \rightarrow 2p^6^1S_0$	9,646(2)	9,6438(7)	
Si V	$3d^3D_1^o \rightarrow 2p^6^1S_0$	9,726(2)	9,715(2)	
Si V	$3d^3P_1^o \rightarrow 2p^6^1S_0$	9,830(5)		
Si VI		9,952(2)		
Si VI		10,092(2)		
Si V	$3s^1P_1^o \rightarrow 2p^6^1S_0$	11,789(2)	11,7846(6)	
Si V	$3s^3P_0^o \rightarrow 2p^6^1S_0$	11,873(2)		
Si V	$3s^3P_1^o \rightarrow 2p^6^1S_0$	11,903(3)	11,8950(7)	
Si V	$3s^3P_2^o \rightarrow 2p^6^1S_0$	11,938(3)	11,907(9)	

Tabelle 4.2: Es sind die Pixelpositionen der Linien, ihre Fehler $\Delta Pixel$, die aus der NIST Datenbank [17] korrespondierenden Wellenlängen λ und deren Fehler $\Delta\lambda$, sowie der Ladungszustand in der Tabelle eingetragen.

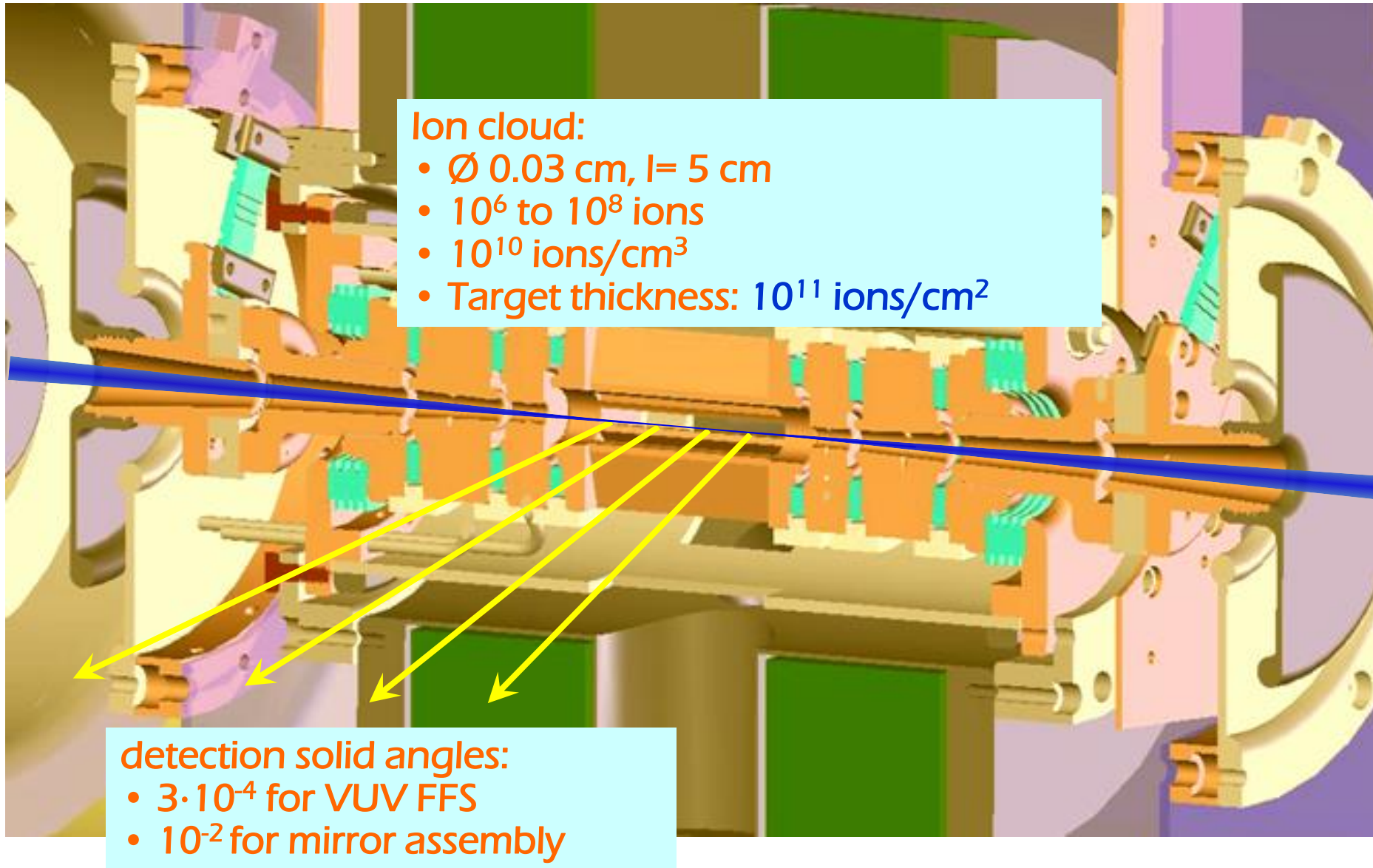
Pixel	$\Delta Pixel$	λ (nm)	$\Delta\lambda$ (nm)	Ladungszustand
43,539	0,029	17,453	0,007	Fe ⁹⁺
61,765	0,107	17,527	0,007	Fe ⁹⁺
108,380	0,058	17,724	0,007	Fe ⁹⁺
336,169	0,035	18,688	0,007	Fe ¹¹⁺
368,306	0,031	18,822	0,007	Fe ¹⁰⁺
455,160	0,080	19,203	0,007	Fe ²³⁺
464,759	0,399	19,239	0,007	Fe ¹¹⁺
490,284	0,079	19,351	0,007	Fe ¹¹⁺
527,308	0,030	19,512	0,007	Fe ¹¹⁺
724,813	0,083	20,383	0,007	Fe ¹²⁺
1064,434	0,155	21,914	0,007	Fe ¹³⁺
1760,207	0,195	25,195	0,007	Fe ¹²⁺
1824,212	0,202	25,511	0,007	Fe ²³⁺
1870,544	0,116	25,726	0,007	Fe ⁹⁺
2021,824	0,221	26,479	0,007	Fe ¹³⁺

Julia Jäger



Julia Jäger

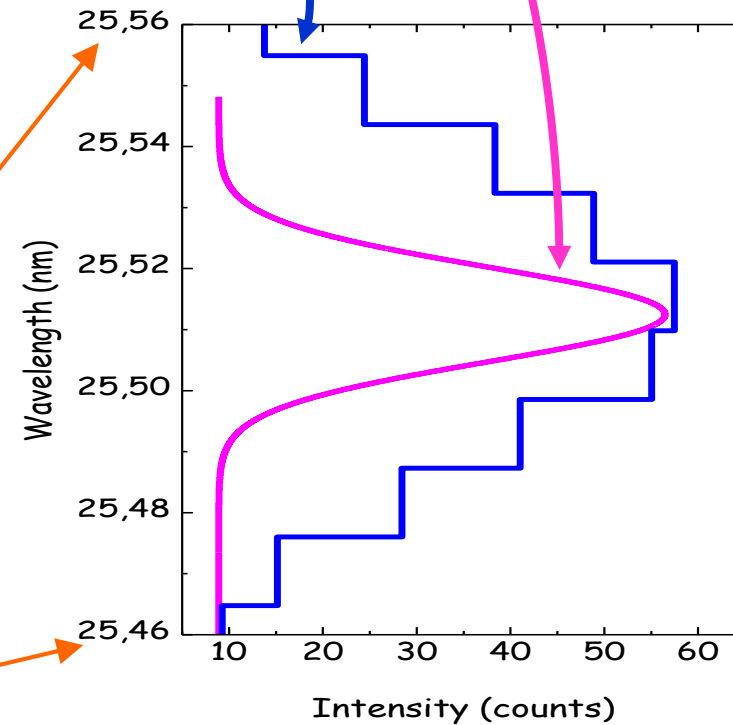
Longitudinal cut through the FLASH-EBIT



Region scanned with FEL

Fe XXIV 19.2028 nm

spectrograph data



Fe XXIV 25.5113 nm (48.5997 eV)

ng spectrometer results

K: Fe XX 12.1858 nm
D: Fe XXI 12.8755 nm
A: Fe XXIII 13.2906 nm
C: Fe XXIII 13.5812 nm

Fe XXIV 19.2028 nm

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F: Fe XXIV 19.2028 nm

2nd Fe XXII 11.441 nm
2nd Fe XXII 11.714 nm

Fe XXII 24.719 nm

Fe XXIV 25.5113 nm

2nd D
2nd A
2nd C

Fe XV 28.4164 nm

Fe XXIV 25.5113 nm (48.5997 nm)

\ C: Fe XXIII 13.5812 nm

102

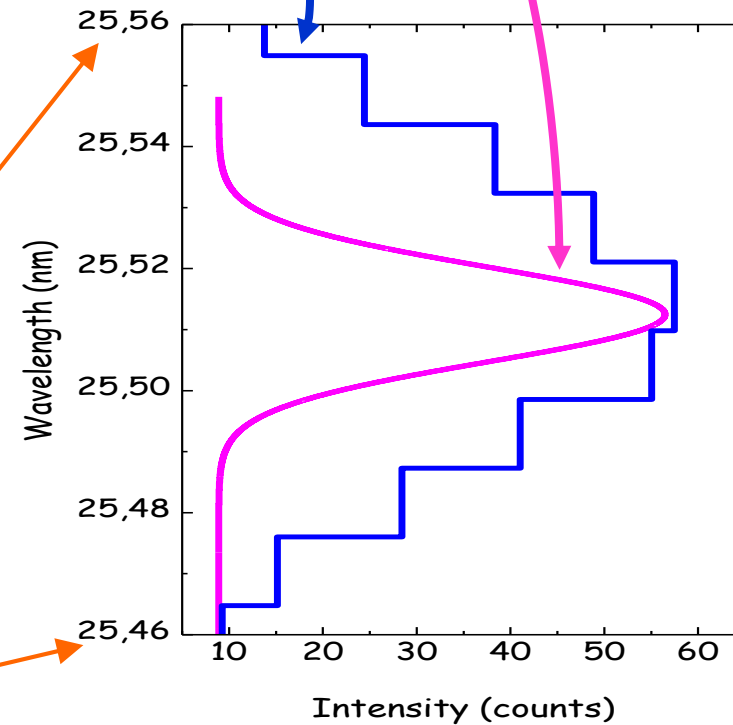
Fe XV 28.4164 nm

Fe XXIV 25.5113 nm (48.5997 eV)

Region scanned with FEL

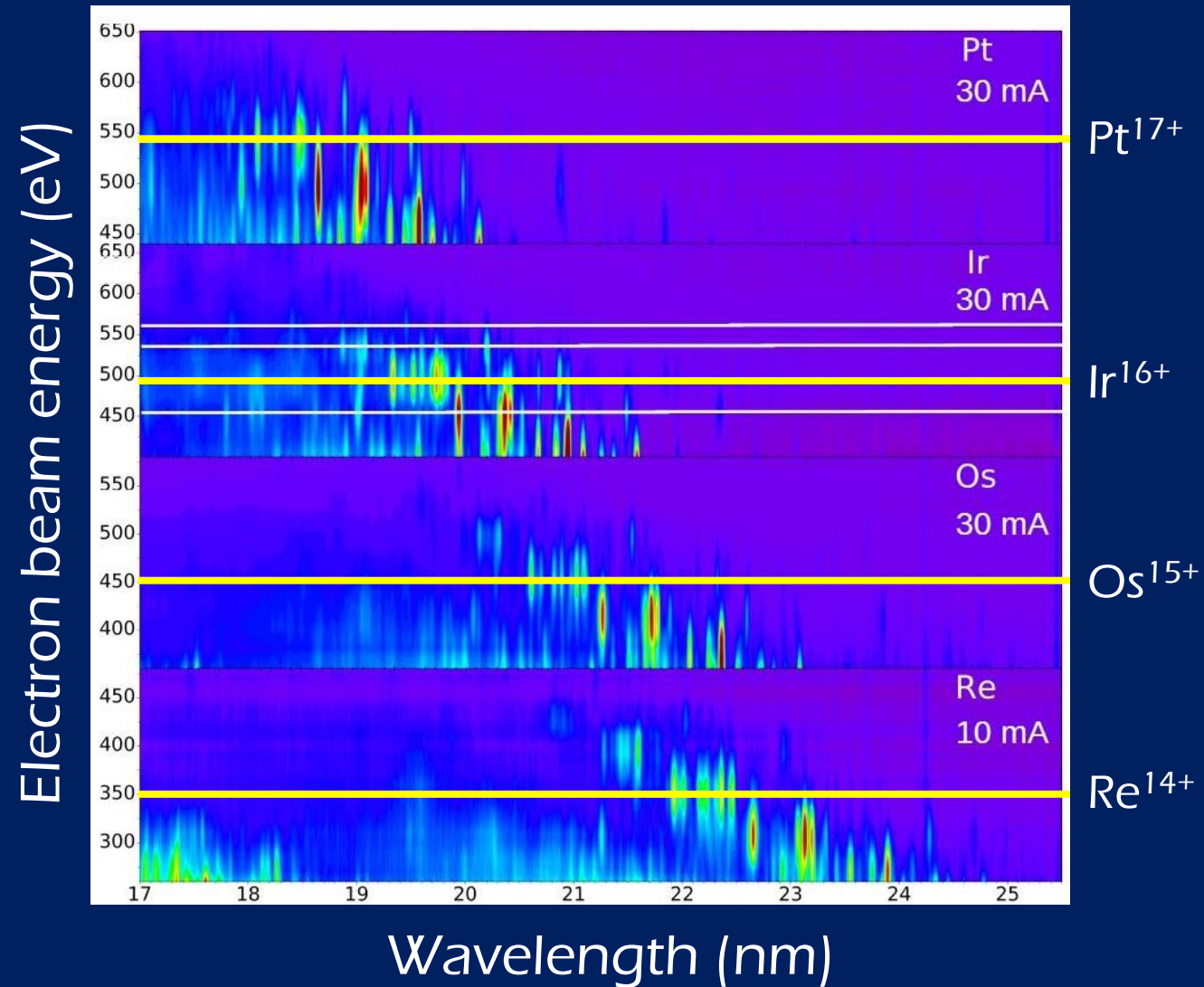
Fe XXIV 19.2028 nm

spectrograph data



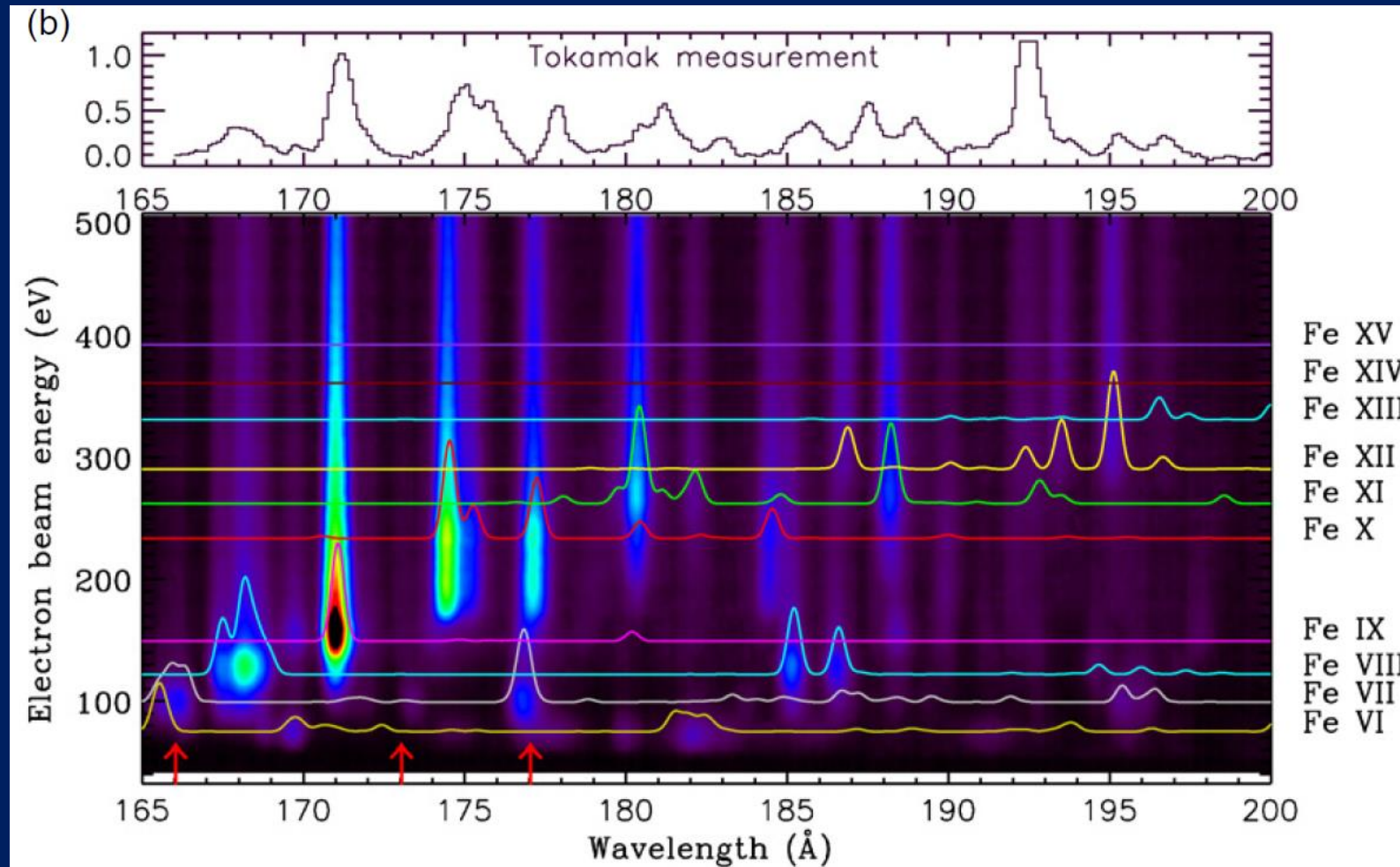
Fe XXIV 25.5113 nm (48.5997 eV)

Pm-like (61 electrons) isoelectronic sequence



Isoelectronic sequence studied in detail to find analogies

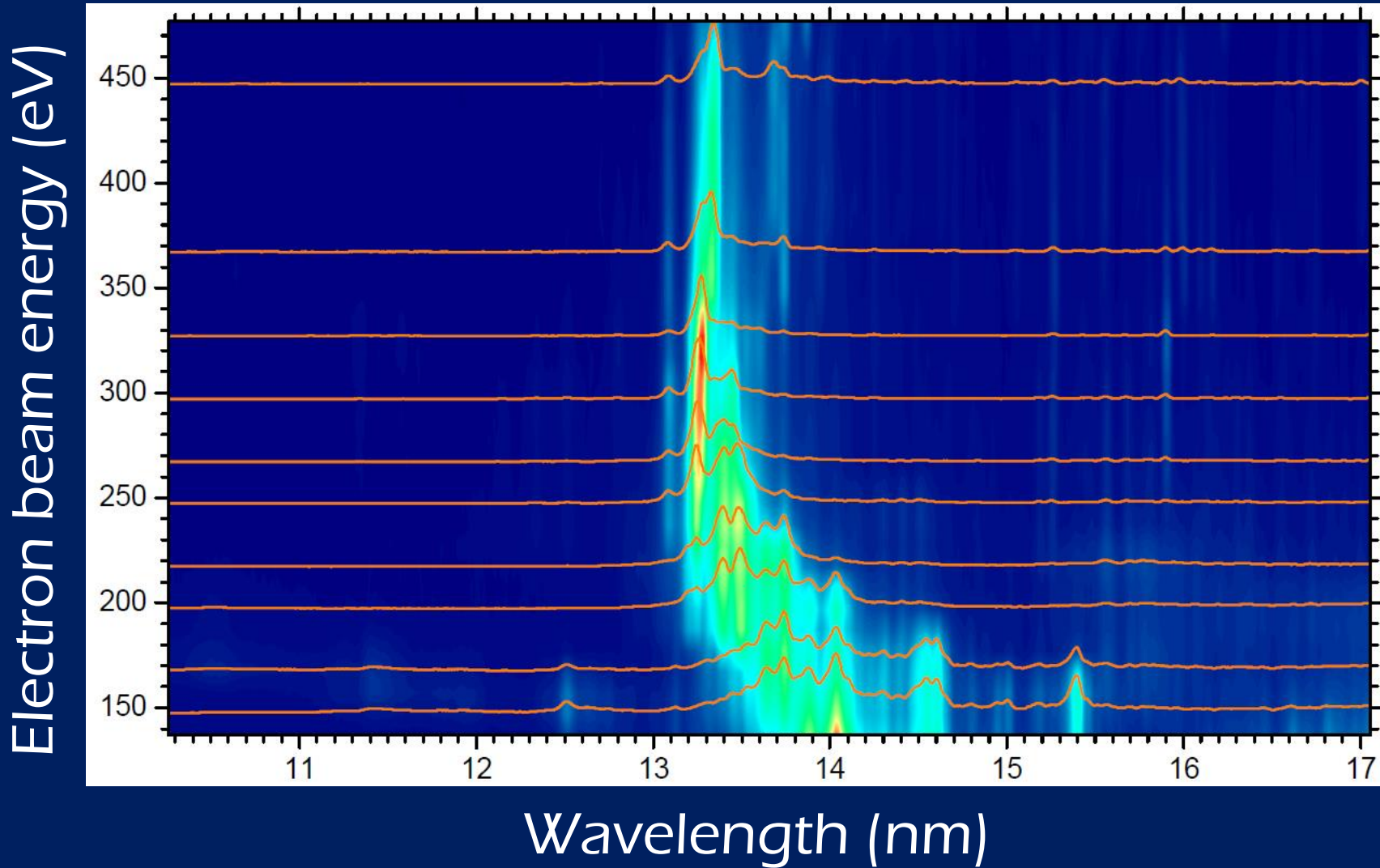
Studies of Fe HCl with charge-state resolution



Gu et al., *Astrophys. J.* 696, 2275 (2009)

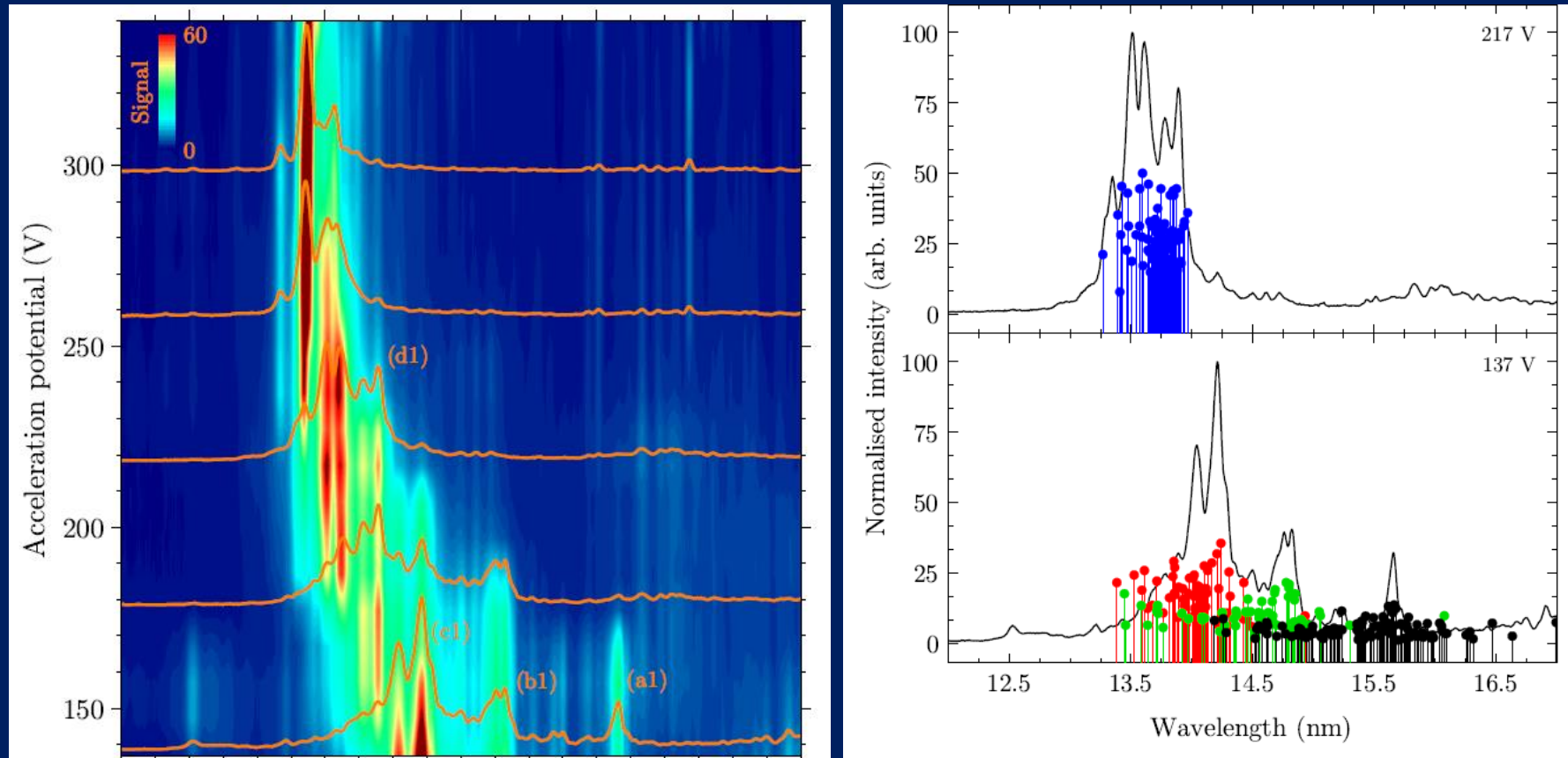
Understanding optical and EUV spectra of Sn ions

Understanding Sn spectra



H. Bekker et al., J. Phys. B **48**, 144018 (2015)

Understanding Sn spectra



F. Torretti, ARCNL, PRA (2017)

